INCH-POUND

MIL-M-38510/301F

4 March 2004

SUPERSEDING

MIL-M-38510/301E

14 February 2003

#### MILITARY SPECIFICATION

#### MICROCIRCUITS, DIGITAL, BIPOLAR LOW-POWER SCHOTTKY TTL, FLIP-FLOPS, CASCADABLE, MONOLITHIC SILICON

Inactive for new design after 18 April 1997.

This specification is approved for use by all Departments and Agencies of the Department of Defense.

The requirements for acquiring the product herein shall consist of this specification sheet and MIL-PRF 38535

- 1. SCOPE
- 1.1 <u>Scope.</u> This specification covers the detail requirements for monolithic silicon, low-power Schottky TTL, flip-flops, bistable logic gate microcircuits. Two product assurance classes and a choice of case outlines and lead finishes are provided for each type and are reflected in the complete part number. For this product, the requirements of MIL-M-38510 have been superseded by MIL-PRF-38535, (see 6.3).
  - 1.2 Part number. The part number is in accordance with MIL-PRF-38535, and as specified herein.
  - 1.2.1 <u>Device types.</u> The device types are as follows:

Device type	<u>Circuit</u>
01	Dual J-K flip-flop with clear
02	Dual D type flip-flop with clear and preset
03	Dual J-K flip-flop with clear and preset
04	Dual J-K flip-flop with preset
05	Dual J-K flip-flop with preset and common clear and common clock
06	Hex D type flip-flop with common clear and common clock
07	Quad D type flip-flop with common clear and common clock
08	Dual, J-K flip-flop with clear
09	Dual, J-K flip-flop with clear and preset
10	Dual, J-K flip-flop with clear and preset

- 1.2.2 <u>Device class</u>. The device class is the product assurance level as defined in MIL-PRF-38535.
- 1.2.3 Case outlines. The case outlines are as designated in MIL-STD-1835 and as follows:

Outline letter	<u>Descriptive designator</u>	<u>Terminals</u>	Package style
Α	GDFP5-F14 or CDFP6-F14	14	Flat pack
В	GDFP4-14	14	Flat pack
С	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
D	GDFP1-F14 or CDFP2-F14	14	Flat pack
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line
F	GDFP2-F16 or CDFP3-F16	16	Flat pack
Χ	CQCC2-N20	20	Square leadless chip carrier
2	CQCC1-N20	20	Square leadless chip carrier

Comments, suggestions, or questions on this document should be addressed to: Commander, Defense Supply Center Columbus, ATTN: DSCC-VAS, 3990 East Broad St., Columbus, OH 43216-5000, or emailed to bipolar@dscc.dla.mil. Since contact information can change, you may want to verify the currency of this address information using the ASSIST Online database at www.dodssp.daps.mil.

AMSC N/A FSC 5962

#### 1.3 Absolute maximum ratings.

Supply voltage range	-0.5 V dc to 7.0 V dc
Input voltage range	-1.5 V dc at -18 mA to 5.5 V dc
Storage temperature range	-65° to +150°C
Maximum power dissipation per flip-flop, (P <sub>D</sub> ) 1/	
Lead temperature (soldering, 10 seconds)	
Thermal resistance, junction to case ( $\theta_{JC}$ ):	
Cases A, B, C, D, E, F, X, and 2	(See MIL-STD-1835)
Junction temperature (T <sub>J</sub> ) <u>2</u> /	175°C

#### 1.4 Recommended operating conditions.

Supply voltage (V <sub>CC</sub> )	2.0 V dc 0.7 V dc
01, 03, 04, 05, 08, 09, and 10	25 ns minimum 20 ns minimum
Device types: 01, 03, 04, 05, 08, and 10 02, 06, 07, and 09	

#### 2. APPLICABLE DOCUMENTS

2.1 <u>General.</u> The documents listed in this section are specified in sections 3, 4, or 5 of this specification. This section does not include documents cited in other sections of this specification or recommended for additional information or as examples. While every effort has been made to ensure the completeness of this list, document users are cautioned that they must meet all specified requirements of documents cited in sections 3, 4, or 5 of this specification, whether or not they are listed.

#### 2.2 Government documents.

2.2.1 <u>Specifications and Standards</u>. The following specifications and standards form a part of this specification to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

#### DEPARTMENT OF DEFENSE SPECIFICATIONS

MIL-PRF-38535 - Integrated Circuits (Microcircuits) Manufacturing, General Specification for.

#### DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard for Microelectronics.

MIL-STD-1835 - Interface Standard Electronic Component Case Outlines

(Copies of these documents are available online at http://assist.daps.dla.mil;quicksearch/ or www.dodssp.daps.mil or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

 $<sup>\</sup>underline{1}$ / Must withstand the added P<sub>D</sub> due to short-circuit test (e.g.,  $I_{OS}$ ).

Maximum junction temperature shall not be exceeded except for allowable short duration burn-in screening conditions in accordance with MIL-PRF-38535.

2.2 <u>Order of precedence.</u> In the event of a conflict between the text of this specification and the references cited herein, the text of this document takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

#### 3. REQUIREMENTS

- 3.1 <u>Qualification</u>. Microcircuits furnished under this specification shall be products that are manufactured by a manufacturer authorized by the qualifying activity for listing on the applicable qualified manufacturers list before contract award (see 4.3 and 6.4).
- 3.2 <u>Item requirements.</u> The individual item requirements shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.
- 3.3 <u>Design, construction, and physical dimensions.</u> The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein.
  - 3.3.1 Terminal connections. The terminal connections shall be as specified on figure 1.
  - 3.3.2 Logic diagrams. The logic diagrams shall be as specified on figure 2.
  - 3.3.3 Truth tables. The truth tables and logic equations shall be as specified on figure 3.
- 3.3.4 <u>Schematic circuits</u>. The schematic circuits shall be maintained by the manufacturer and made available to the qualifying activity and the preparing activity upon request.
  - 3.3.5 Case outlines. The case outlines shall be as specified in 1.2.3.
  - 3.4 Lead material and finish. The lead material and finish shall be in accordance with MIL-PRF-38535 (see 6.6).
- 3.5 <u>Electrical performance characteristics</u>. The electrical performance characteristics are as specified in table I, and apply over the full recommended case operating temperature range, unless otherwise specified.
- 3.6 <u>Electrical test requirements.</u> The electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.
  - 3.7 Marking. Marking shall be in accordance with MIL-PRF-38535.
- 3.8 <u>Microcircuit group assignment.</u> The devices covered by this specification shall be in microcircuit group number 10 (see MIL-PRF-38535, appendix A).

#### 4. VERIFICATION

- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not effect the form, fit, or function as described herein.
- 4.2 <u>Screening.</u> Screening shall be in accordance with, MIL-PRF-38535 and shall be conducted on all devices prior to qualification and quality conformance inspection. The following additional criteria shall apply:
  - a. The burn-in test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
  - b. Interim and final electrical test parameters shall be as specified in table II, except interim electrical parameters test prior to burn-in is optional at the discretion of the manufacturer.
  - c. Additional screening for space level product shall be as specified in MIL-PRF-38535, appendix B.
  - 4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-PRF-38535.
- 4.4 <u>Technology Conformance inspection (TCI)</u>. Technology conformance inspection shall be in accordance with MIL-PRF-38535 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).
  - 4.4.1 Group A inspection. Group A inspection shall be in accordance with table III of MIL-PRF-38535 and as follows:
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 4, 5, and 6 shall be omitted.
  - 4.4.2 Group B inspection. Group B inspection shall be in accordance with table II MIL-PRF-38535.
  - 4.4.3 Group C inspection. Group C inspection shall be in accordance with table IV of MIL-PRF-38535 and as follows:
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. The steady-state life test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
- 4.4.4 <u>Group D inspection.</u> Group D inspection shall be in accordance with table V of MIL-PRF-38535. End-point electrical parameters shall be as specified in table II herein.
  - 4.5 Methods of inspection. Methods of inspection shall be specified and as follows:
- 4.5.1 <u>Voltage and current</u>. All voltages given are referenced to the microcircuit ground terminal. Currents given are conventional and positive when flowing into the referenced terminal.

TABLE I. <u>Electrical performance characteristics.</u>

Test	Symbol	Conditions 1/	Device	Li	Limits		
		-55°C ≤ T <sub>C</sub> ≤ +125°C	types	Min	Max		
		unless otherwise specif					
High level output	V <sub>OH</sub>	V <sub>CC</sub> = 4.5 V,		All	2.5		V
voltage		I <sub>OH</sub> = -400 μA					
Low level output	V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 4 mA		All		0.4	V
voltage							
Input clamp voltage	V <sub>IC</sub>	$V_{CC} = 4.5 \text{ V}, I_{IN} = -18 \text{ mA},$		All		-1.5	V
		T <sub>C</sub> = +25°C					
Low level input	I <sub>IL1</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 0.4 \text{ V}$	<u>2</u> /	01, 03,	030	360	mA
current				04	010	360	
				05, 08, 10			
			<u>2</u> /	06, 07	075	400	
	I <sub>IL2</sub>		<u>3</u> /	02, 09	030	400	
			<u>3</u> /	06	075	420	
			<u>3</u> /	07	075	420	
	I <sub>IL3</sub>		<u>4</u> /	01, 08	060	720	
	120		<u>4</u> /	03, 04, 10	060	760	
	I <sub>IL4</sub>		<u>5</u> /	01, 02, 03,	060	800	
	124			04, 05, 08,			
				09, 10			
	I <sub>IL5</sub>		<u>6</u> /	02	060	-1.20	
	I <sub>IL6</sub>		<u>4</u> /	05	12	-1.52	
	I <sub>IL7</sub>		<u>6</u> /	05	120	-1.60	
			6/	09	060	-1.60	
High level input current	I <sub>IH1</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 2.7 \text{ V}$	<u>7</u> /	All		20	μΑ
	I <sub>IH2</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 5.5 \text{ V}$	<u>7</u> /	All		100	
	I <sub>IH3</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 2.7 \text{ V}$	<u>8</u> /	02, 09		40	
	I <sub>IH4</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 5.5 \text{ V}$	<u>8</u> /	02, 09		200	
	I <sub>IH5</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 2.7 \text{ V}$	<u>9</u> /	01, 02, 03, 04, 05, 08, 10		60	
	I <sub>IH6</sub>	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 5.5 V	<u>9</u> /	01, 02, 03, 04, 05, 08, 10		300	
	I <sub>IH7</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 2.7 \text{ V}$	<u>10</u> /	01, 03, 04, 08, 09, 10		80	
	I <sub>IH8</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 5.5 \text{ V}$	<u>10</u> /	01, 03, 04, 08, 09, 10		400	
	I <sub>IH9</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 2.7 \text{ V}$	<u>6</u> /	05		120	
	I <sub>IH10</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 5.5 \text{ V}$	<u>6</u> /	05		600	
	I <sub>IH11</sub>	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 2.7 V	<u>4</u> /	05		160	1
	I <sub>IH12</sub>	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 5.5 V	<u>4</u> /	05		800	

See footnotes at end of table.

TABLE I. <u>Electrical performance characteristics</u> - Continued.

Test	Symbol	Conditions 1/	Device	L	imits	Unit
		-55°C ≤ T <sub>C</sub> ≤ +125°C	types	Min	Max	
		unless otherwise specified				
Short circuit output	Ios	V <sub>CC</sub> = 5.5 V <u>11</u> /	01, 02, 03,	-15	-100	mA
current		V <sub>IN</sub> = 0 V	05, 06, 07,			
			08, 09			
			04, 10	-15	-130	
Supply current	Icc	$V_{CC} = 5.5 \text{ V}, V_{IN} = 5.5 \text{ V}$	01, 02, 03,		8	mA
			04, 05, 08			
			09, 10			
			06		26	
			07		18	
Maximum clock	f <sub>MAX</sub>	$V_{CC} = 5.0 \text{ V}$	01, 03, 04	25		MHz
frequency		$C_L = 50 \text{ pF} \pm 10\%$	05, 06, 07			
		$R_L = 2k\Omega \pm 5\%$	08, 10			
			02, 09	20		
Propagation delay to	t <sub>PLH1</sub>		01, 03, 04,	5	32	ns
high logic level			05, 08, 10			
(clear or preset			02, 09	5	39	
to output)			07	5	51	
Propagation delay to	t <sub>PHL1</sub>		01, 03, 04,	5	40	ns
low logic level			05, 08, 10			
(clear or preset			02, 09	5	59	
to output)			06	5	52	
. ,			07	5	55	
Propagation delay to	t <sub>PLH2</sub>		01, 03, 04,	5	32	ns
high logic level			05, 08, 10			
(clock to output)			02, 09	5	39	
. ,			06	5	47	
			07	5	46	
Propagation delay to	t <sub>PHL2</sub>	1	01, 03, 04,	5	42	ns
low logic level			05, 08, 10			
(clock to output)			02, 09	5	59	
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \			06	5	52	
			07	5	55	

- 1/ See table III for complete terminal conditions.
- 2/ Input condition J or K (device types 01, 03, 04, 05, 08, and 10); and D (device types 06 and 07).
- $\underline{3}$ / Input condition D (device type 02); clock or clear (device types 06 and 07); and J or  $\overline{K}$  (device type 09).
- 4/ Input condition Clock.
- 5/ Input condition Clear or preset (device types 03 and 10); clear (device types 01 and 08); preset or clock (device types 02 and 09); and preset (device types 04 and 05).
- 6/ Input condition Clear.
- 7/ Input condition J or K (device types 01, 03, 04, 05, 08, and 10); D (device type 02); J or K (device type 09); and D, clear, clock (device types 06 and 07).
- 8/ Input condition Preset or clock.
- 9/ Input condition Clear or preset (device types 03 and 10); clear (device types 01, 02, and 08); and preset (device types 04 and 05).
- 10/ Input condition Clock (device type 01, 03, 04, 08, and 10); and clear (device type 09).
- 11/ Not more than one output should be shorted at a time.

TABLE II. Electrical test requirements.

	Subgroups	(see table III)
MIL-PRF-38535	Class S	Class B
test requirements	devices	devices
Interim electrical parameters	1	1
Final electrical test parameters	1*, 2, 3, 7, 9, 10, 11	1*, 2, 3, 9
Group A test requirements	1, 2, 3, 7, 8, 9, 10, 11	1, 2, 3, 7, 8, 9, 10, 11
Group C end-point electrical parameters	1, 2, 3, 9, 10, 11	1, 2, 3
Group D end-point electrical parameters	1, 2, 3	1, 2, 3

<sup>\*</sup>PDA applies to subgroup 1.

#### 5. PACKAGING

5.1 <u>Packaging requirements.</u> For acquisition purposes, the packaging requirements shall be as specified in the contract or order (see 6.2). When actual packaging of materiel is to be performed by DoD personnel, these personnel need to contact the responsible packaging activity to ascertain requisite packaging requirements. Packaging requirements are maintained by the Inventory Control Point's packaging activity within the Military Department of Defense Agency, or within the Military Department's System Command. Packaging data retrieval is available from the managing Military Department's or Defense Agency's automated packaging files, CD-ROM products, or by contacting the responsible packaging activity.

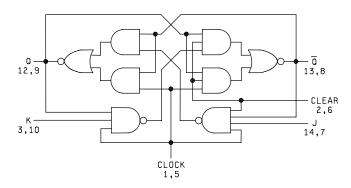
		ymbols type 01		ymbols type 02		mbols type 03		ymbols type 04		ymbols type 05
Pin	Cases	Cases	Cases	Cases	Cases	Cases	Cases	Cases	Cases	Cases
number	2, X	A, B, C, and D	2, X	A, B, C, and D	2, X	E, F	2, X	A, B, C, and D	2, X	A, B, C, and D
1	NC	CLK1	NC	CLR1	NC	CLK1	NC	CLK1	NC	CLR1
2	CLK1	CLR1	CLR1	1D	CLK1	1K	CLK1	1K	CLR	1K
3	CLR1	1K	1D	CLK1	1K	1J	1K	1J	1K	1J
4	1K	V <sub>CC</sub>	CLK1	PS1	1J	PS1	1J	PS1	1J	PS1
5	NC	CLK2	NC	1Q	PS1	1Q	NC	1Q	NC	1Q
6	Vcc	CLR2	PS1	1 Q	NC	1 Q	PS1	1 Q	PS1	1 Q
7	NC	2J	NC	GND	1Q	2 <del>Q</del>	NC	GND	NC	GND
8	CLK2	2 \overline{Q}	1Q	2 \overline{Q}	1 Q	GND	1Q	2 Q	1Q	2 \overline{Q}
9	CLR2	2Q	1 Q	2Q	2 Q	2Q	1 Q	2Q	1 Q	2Q
10	2J	2K	GND	PS2	GND	PS2	GND	PS2	GND	PS2
11	NC	GND	NC	CLK2	NC	2J	NC	2J	NC	2J
12	2 \overline{Q}	1Q	2 \overline{Q}	2D	2Q	2K	2 Q	2K	2 \overline{Q}	2K
13	2Q	1 Q	2Q	CLR2	PS2	CLK2	2Q	CLK2	2Q	CLK
14	2K	1J	PS2	V <sub>CC</sub>	2J	CLR2	PS2	V <sub>CC</sub>	PS2	V <sub>CC</sub>
15	NC		NC		2K	CLR1	NC		NC	
16	GND		CLK2		NC	$V_{CC}$	2J		2J	
17	NC		NC		CLK2		NC		NC	
18	1Q		2D		CLR2		2K		2K	
19	1 Q		CLR2		CLR1		CLK2		CLK	
20	1J		V <sub>CC</sub>		V <sub>CC</sub>		V <sub>CC</sub>		V <sub>CC</sub>	

FIGURE 1. <u>Terminal connections</u>.

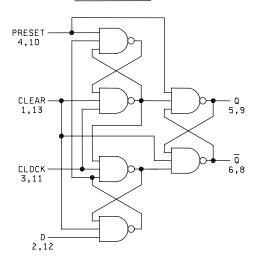
		ymbols type 06		mbols type 07		mbols type 08		ymbols type 09		ols device e 10
Pin number	Cases 2, X	Cases E, F	Cases 2, X	Cases E, F	Cases 2, X	Cases A, B, C, and D	Cases 2, X	Cases E, F	Cases 2, X	Cases E, F
1	NC	CLR	NC	CLR	NC	1J	NC	1CLR	NC	1CLK
2	CLR	1Q	CLR	1Q	1J	1 Q	1CLR	1J	1CLK	1PS
3	1Q	1D	1Q	1 Q	1 Q	1Q	1J	1 K	1PS	1CLR
4	1D	2D	1 Q	1D	1Q	1K	1 K	1CLK	1CLR	1J
5	2D	2Q	1D	2D	NC	2Q	1CLK	1PS	1J	V <sub>CC</sub>
6	NC	3D	NC	2 \overline{Q}	1K	2 <del>Q</del>	NC	1Q	NC	2CLK
7	2Q	3Q	2D	2Q	NC	GND	1PS	1 Q	V <sub>CC</sub>	2PS
8	3D	GND	2 Q	GND	2Q	2J	1Q	GND	2CLK	2CLR
9	3Q	CLK	2Q	CLK	2 \( \overline{Q} \)	2CLK	1 Q	2 \overline{Q}	2PS	2J
10	GND	4Q	GND	3Q	GND	2CLR	GND	2Q	2CLR	2 Q
11	NC	4D	NC	3 Q	NC	2K	NC	2PS	NC	2Q
12	CLK	5Q	CLK	3D	2J	1CLK	2 Q	2CLK	2J	2K
13	4Q	5D	3Q	4D	2CLK	1CLR	2Q	2K	2 Q	GND
14	4D	6D	3 Q	4 Q	2CLR	V <sub>CC</sub>	2PS	2J	2Q	1 Q
15	5Q	6Q	3D	4Q	NC		2CLK	2CLR	2K	1Q
16	NC	$V_{CC}$	NC	V <sub>CC</sub>	2K		NC	$V_{CC}$	NC	1K
17	5D		4D		NC		2K		GND	
18	6D		4 Q		1CLK		2J		1 Q	
19	6Q		4Q		1CLR		2CLR		1Q	
20	V <sub>CC</sub>		V <sub>CC</sub>		V <sub>CC</sub>		V <sub>CC</sub>		1K	

FIGURE 1. <u>Terminal connections</u> - Continued.

#### DEVICE TYPE 01



#### DEVICE TYPE 02



DEVICE TYPE 03

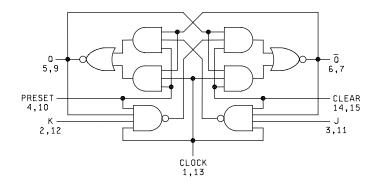
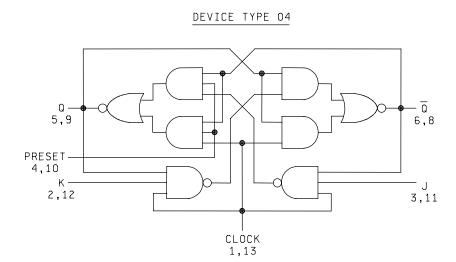


FIGURE 2. Logic Diagrams.



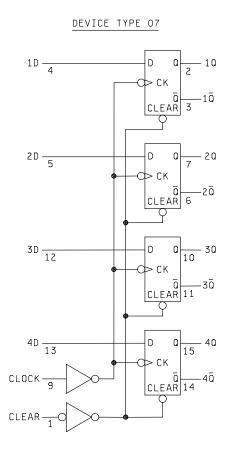
# PRESET 4,10 CLOCK 13 TO OTHER FLIP FLOP

FIGURE 2. Logic Diagrams - Continued.

DEVICE TYPE 06

### 2D <u>4</u> CLEAR 3D <u>6</u> CLEAR 4D 11 CLEAR 5D <u>13</u> 0 12 50 ф ск CLEAR > CK

FIGURE 2. Logic Diagrams - Continued.



#### DEVICE TYPE 08

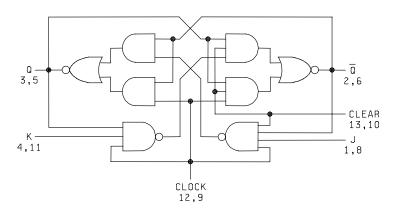
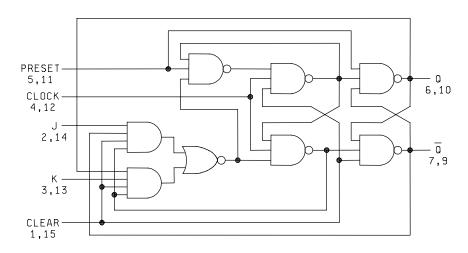


FIGURE 2. Logic Diagrams - Continued.

#### DEVICE TYPE 09



#### DEVICE TYPE 10

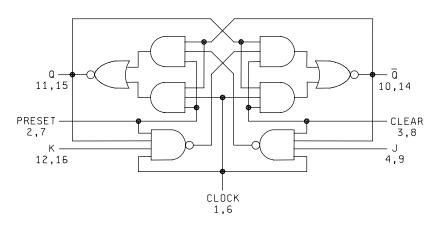


FIGURE 2. Logic Diagrams - Continued.

#### **DEVICE TYPE 01**

	OUTI	PUTS			
CLEAR	CLOCK	٦	K	Q	IØ
L	Х	Х	Х	L	Н
Н	<b>↓</b>	L	L	$Q_0$	$\overline{Q}_0$
Н	$\downarrow$	Н	L	Н	L
Н	$\downarrow$	┙	Н	┙	Η
Н	$\downarrow$	Η	Н	TOGGLE	
Н	Н	Χ	X	$Q_0$	o  Q

H = high level (steady state)

L = low level (steady state)

X = irrelevant

 $\downarrow$  = transition from high to low level

 $Q_0$  = the level of Q before the indicated input conditions were established.

TOGGLE: Each output changes to the complement of its previous level on each ↓ clock transition.

#### **DEVICE TYPE 02**

	OUTF	PUTS			
PRESET	CLEAR	CLOCK	D	Q	IØ
L	Н	Х	Х	Н	L
Н	L	Χ	Χ	L	Н
L	L	Χ	Χ	H*	H*
Н	Η	1	Η	Н	L
Н	Н	1	L	L	Н
Н	Н	L	Χ	$Q_0$	Q <sub>0</sub>

H = high level (steady state)

L = low level (steady state)

X = irrelevant

 $\uparrow$  = transition from low to high level

Q<sub>0</sub> = the level of Q before the indicated steady state input conditions were established.

\* This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

FIGURE 3. Truth tables.

#### **DEVICE TYPES 03 AND 10**

	OUTF	PUTS				
PRESET	CLEAR	CLOCK	J	K	Q	Q
L	Н	Х	Х	Х	Н	L
Н	L	Χ	X	Χ	L	Н
L	L	X	X	Χ	H*	H*
Н	Н	<b>↓</b>	L	L	$Q_0$	$\overline{\overline{Q}}_0$
Н	Н	$\downarrow$	Η	┙	Н	L
Н	Н	$\downarrow$	L	Η	L	Н
Н	Н	<b>↓</b>	Н	Н	TOGGLE	
Н	Н	Н	Х	Х	$Q_0$	$\overline{Q}_0$

H = high level (steady state)

L = low level (steady state)

X = irrelevant

↓ = transition from high to low level

Q<sub>0</sub> = the level of Q before the indicated steady state input conditions were established.

TOGGLE: Each output changes to the complement of its previous level on each ↓ clock transition.

\* This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

**DEVICE TYPE 04** 

	INPUT		OUTPUTS			
PRESET	CLOCK	J	K	Q	IQ	
L	Н	Х	Х	Н	L	
Н	<b>↓</b>	L	L	$Q_0$	$\overline{Q}_0$	
Н	$\downarrow$	Н	L	Н	L	
Н	$\downarrow$	L	Н	┙	Η	
Н	$\downarrow$	Н	Н	TOG	GLE	
Н	Н	X	X	$Q_0$	$\overline{Q}_{0}$	

H = high level (steady state)

L = low level (steady state)

X = irrelevant

↓ = transition from high to low level

Q<sub>0</sub> = the level of Q before the indicated input conditions were established.

TOGGLE: Each output changes to the complement of its previous level on each ↓ clock transition.

FIGURE 3. <u>Truth tables</u> - Continued.

#### **DEVICE TYPES 05**

		INPUTS						
PRESET	CLEAR	CLOCK	J	K	Q	Q		
L	Н	Х	X	X	Н	L		
Н	L	Χ	X	Χ	L	Н		
L	L	X	X	Χ	H*	H*		
Н	Н	<b>↓</b>	L	L	$Q_0$	$\overline{\overline{Q}}_0$		
Н	Н	$\downarrow$	Η	┙	Н	L		
Н	Н	$\downarrow$	L	Η	L	Н		
Н	Н	$\downarrow$	Η	Η	TOG	GLE		
Н	Н	Н	Х	Х	$Q_0$	$\overline{Q}_0$		

H = high level (steady state)

L = low level (steady state)

X = irrelevant

↓ = transition from high to low level

 $\dot{Q}_0$  = the level of Q before the indicated steady state input conditions were established.

TOGGLE: Each output changes to the complement of its previous level on each ↓ clock transition.

\* This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

#### **DEVICE TYPE 06**

	INPUTS						
CLEAR	CLOCK	D	OUTPUT Q				
L	Х	Х	L				
Н	<b>↑</b>	Н	Н				
Н	<b>↑</b>	L	L				
Н	L	X	$Q_0$				

H = high level (steady state)

L = low level (steady state)

X = irrelevant

↑ = transition from low to high level

Q<sub>0</sub> = the level of Q before the indicated steady state input conditions were established.

FIGURE 3. Truth tables - Continued.

#### **DEVICE TYPE 07**

	INPUTS		OUTPUT			
CLEAR	CLOCK	D	Q	Q		
L	Х	Х	L	Н		
Н	<b>↑</b>	Н	Ι	L		
Н	1	L	L	L		
Н	L	Х	$Q_0$	$\overline{\overline{Q}}_0$		

H = high level (steady state) L = low level (steady state)

X = irrelevant

 $\uparrow$  = transition from low to high level

 $Q_0$  = the level of Q before the indicated steady state input conditions were established.

#### **DEVICE TYPE 08**

	INPUT	S		OUTPUTS			
CLEAR	CLOCK	٦	K	Q	IØ		
L	Х	Х	Х	L	Н		
Н	<b>↑</b>	L	L	$Q_0$	$\overline{Q}_0$		
Н	1	Н	L	Н	L		
Н	1	Ĺ	Н	L	Н		
Н	<b>↑</b>	Н	Н	TOG	GLE		

H = high level (steady state) L = low level (steady state)

X = irrelevant

↑ = transition from low to high level

 $Q_0$  = the level of Q before the indicated input conditions were established.

TOGGLE: Each output changes to the complement of its previous level on each clock transition.

FIGURE 3. Truth tables - Continued.

#### **DEVICE TYPE 09**

		INPUTS			OUTP	UTS	
PRESET	CLEAR	CLOCK	J	K	Q	IØ	
L	Н	Χ	Χ	Χ	Н	L	
Н	L	Χ	Χ	Χ	L	Ι	
L	L	Χ	Χ	Χ	H*	H*	
Н	Н	<b>↑</b>	L	L	L	Ι	
Н	Н	<b>↑</b>	Ι	Ц	TOGGLE		
Н	Н	<b>↑</b>	L	Η	$Q_0$	Q 0	
Н	Н	<b>↑</b>	Н	Н	Н	Ĺ	
Н	Н	L	X	Х	$Q_0$	$\overline{Q}_0$	

H = high level (steady state)

L = low level (steady state)

X = irrelevant

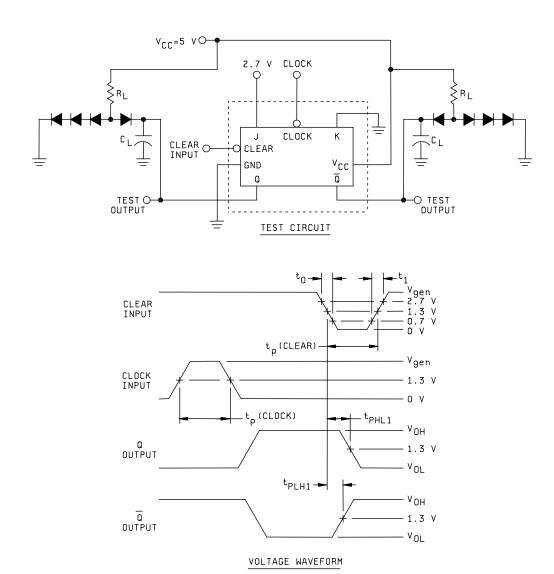
 $\uparrow$  = transition from low to high level

 $\dot{Q}_0$  = the level of Q before the indicated steady state input conditions were established.

TOGGLE: Each output changes to the complement of its previous level on each ↑ clock transition.

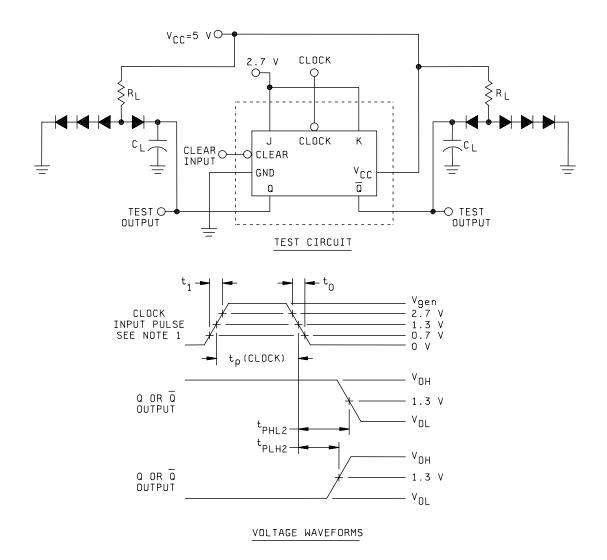
\* This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

FIGURE 3. <u>Truth tables</u> - Continued.



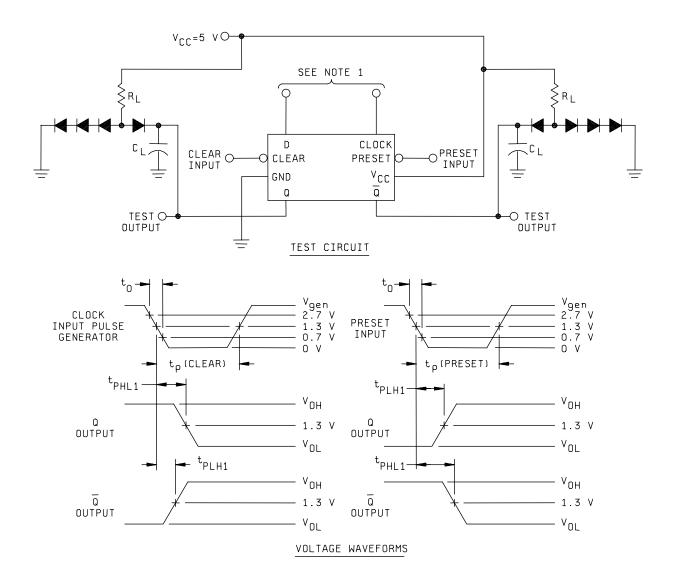
- 1. Clear inputs dominate regardless of the state of clock or J-K inputs.
- 2. Clear input pulse characteristics:  $V_{gen}$  = 3 V,  $t_1 \le 15$  ns,  $t_0 \le 6$  ns,  $t_p$  (clear) = 30 ns, PRR  $\le 1$  MHz.
- 3. All diodes are 1N3064, or equivalent.
- 4.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 5.  $R_L = 2 k\Omega \pm 5\%$ .
- 6. Clock input pulse characteristics:  $V_{gen}$  = 3 V,  $t_p(clock)$  = 25 ns, PRR  $\leq$  1 MHz.

FIGURE 4. Clear switching time test circuit and waveforms for device types 01 and 08.



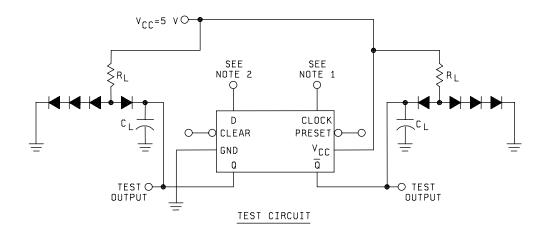
- 1. Clock input characteristics for  $t_{PLH}$ ,  $t_{PHL}$  (clock to output),  $V_{gen} = 3$  V,  $t_1 \le 15$  ns,  $t_0 \le 6$  ns,  $t_p$  (clock) = 25 ns, PRR  $\le 1$  MHz. When testing  $f_{MAX}$  the clock input characteristics are  $V_{gen} = 3$  V,  $t_1 = t_0 \le 6$  ns,  $t_p$  (clock)  $\le 25$  ns, and PRR = see table III.
- 2. All diodes are 1N3064, or equivalent.
- 3.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 4.  $R_L = 2 k\Omega \pm 5\%$ .

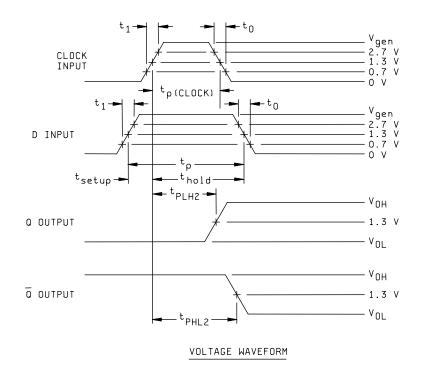
FIGURE 5. Synchronous switching test circuit for device types 01 and 08.



- 1. Clear and preset inputs dominate regardless of the state of clock or D inputs.
- 2. All diodes are 1N3064, or equivalent.
- 3. Clear or preset input pulse characteristics:  $V_{\text{gen}} = 3 \text{ V}$ ,  $t_0 \le 6 \text{ ns}$ ,  $t_p$  (clear) =  $t_p$  (preset) = 35 ns, PRR  $\le 1 \text{ MHz}$ .
- 4.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 5.  $R_1 = 2 k\Omega \pm 5\%$ .
- 6. When testing clear to output switching, preset input shall have a logical "1" voltage applied. When testing preset to output switching, clear input shall have a logical "1" voltage applied (see table III).

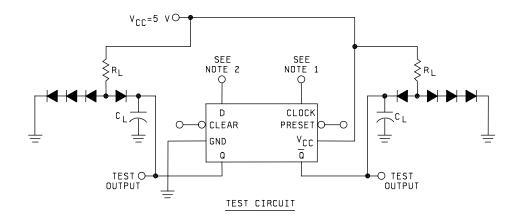
FIGURE 6. Clear and preset switching test circuit and waveforms for device type 02.

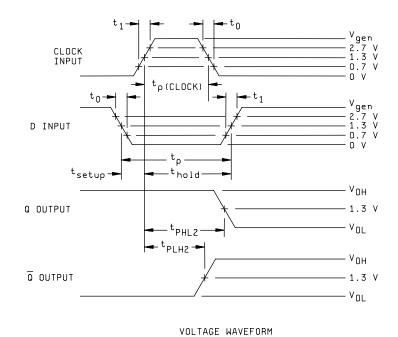




- 1. Clock input pulse has the following characteristics:  $V_{gen} = 3 \text{ V}$ ,  $t_1 \le 15 \text{ ns}$ ,  $t_0 \le 6 \text{ ns}$ ,  $t_p$  (clock) = 30 ns, PRR  $\le 1 \text{ MHz}$ . When testing  $f_{MAX}$ , PRR = see table III,  $t_p$  (clock)  $\le 30 \text{ ns}$ , and  $t_0 = t_1 \le 6 \text{ ns}$ .
- 2. D input has the following characteristics:  $V_{gen} = 3 \text{ V}$ ,  $t_1 \le 15 \text{ ns}$ ,  $t_0 \le 6 \text{ ns}$ ,  $t_{setup} = 20 \text{ ns}$ ,  $t_{hold} = 5 \text{ ns}$ ,  $t_p = 25 \text{ ns}$ , and PRR is 50% of the clock PRR. For  $f_{MAX}$ ,  $t_0 = t_1 \le 6 \text{ ns}$ .
- 3. All diodes are 1N3064, or equivalent.
- 4.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 5.  $R_L = 2 k\Omega \pm 5\%$ .

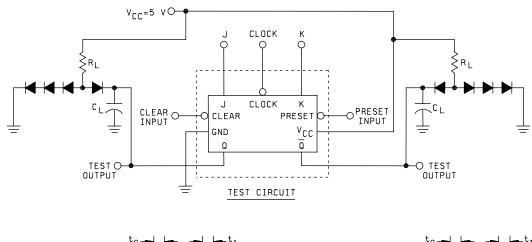
FIGURE 7. Synchronous switching test circuit (high-level data) for device type 02.

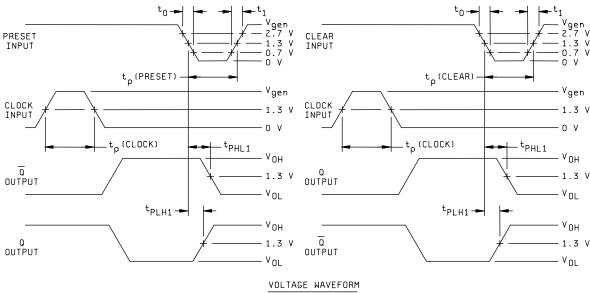




- 1. Clock input pulse has the following characteristics:  $V_{gen}=3$  V,  $t_1 \le 15$  ns,  $t_0 \le 6$  ns,  $t_p$  (clock) = 30 ns, PRR  $\le 1$  MHz. 2. D input has the following characteristics:  $V_{gen}=3$  V,  $t_1 \le 15$  ns,  $t_0 \le 6$  ns,  $t_{setup}=20$  ns,  $t_{hold}=5$  ns,  $t_p=25$  ns, and PRR is 50% of the clock PRR.
- 3. All diodes are 1N3064, or equivalent.
- 4.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 5.  $R_L = 2 k\Omega \pm 5\%$ .

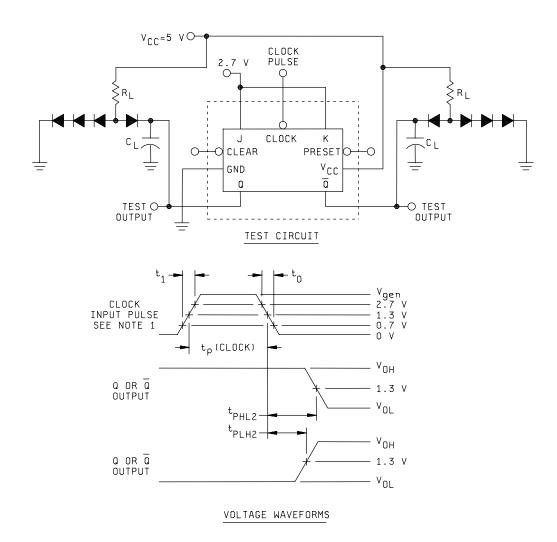
FIGURE 8. Synchronous switching test circuit (low-level data) for device type 02.





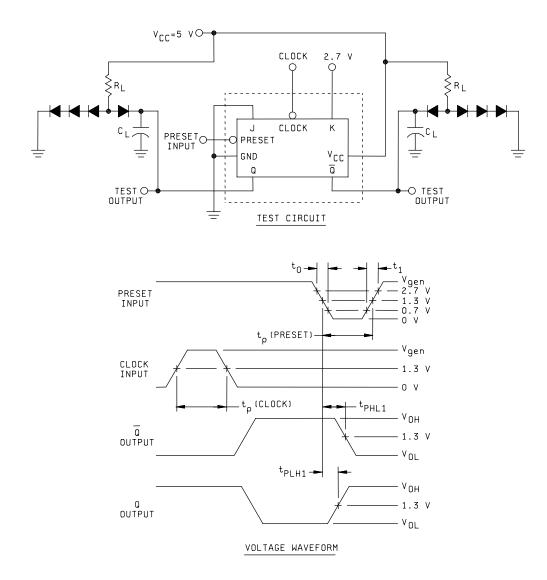
- 1. Clear or preset inputs dominate regardless of the state of clock or J-K inputs.
- 2. Clear or preset input has the following characteristics:  $V_{gen} = 3 \text{ V}$ ,  $t_1 \le 15 \text{ ns}$ ,  $t_0 \le 6 \text{ ns}$ ,  $t_p(\text{clear}) = t_p(\text{preset}) = 30 \text{ ns}$ ,  $\text{PRR} \le 1 \text{ MHz}$ , and  $Z_{out} \approx 50\Omega$ .
- 3.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 4.  $R_L = 2 k\Omega \pm 5\%$ .
- 5. All diodes are 1N3064, or equivalent.
- 6. When testing clear to output switching, preset input shall have a logical "1" voltage applied. When testing preset to output switching, clear input shall have a logical "1" voltage applied. (see table III).
- 7. Clock input pulse characteristics:  $t_p(clock) \ge 25$  ns,  $V_{gen} = 3$  V, PRR  $\le 1$  MHz.

FIGURE 9. Clear and preset switching test circuit and waveforms for device types 03, 05, and 10.



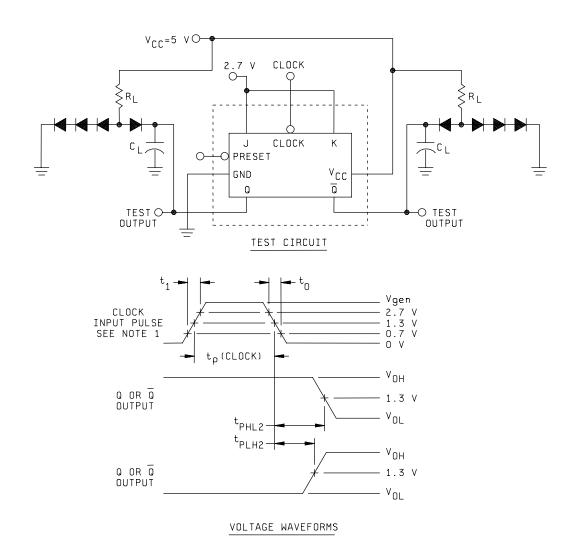
- 1. Clock input characteristics for  $t_{PLH}$ ,  $t_{PHL}$  (clock to output),  $V_{gen} = 3$  V,  $t_0 \le 6$  ns,  $t_1 \le 15$  ns,  $t_p(clock) = 25$  ns, PRR  $\le 1$  MHz. When testing  $t_{MAX}$  the clock input characteristics are  $V_{gen} = 3$  V,  $t_1 = t_0 \le 6$  ns,  $t_p$  (clock)  $\le 25$  ns, and PRR = see table III.
- 2. All diodes are 1N3064, or equivalent.
- 3.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 4.  $R_L = 2 k\Omega \pm 5\%$ .

FIGURE 10. Synchronous switching test circuit for device types 03, 05, and 10.



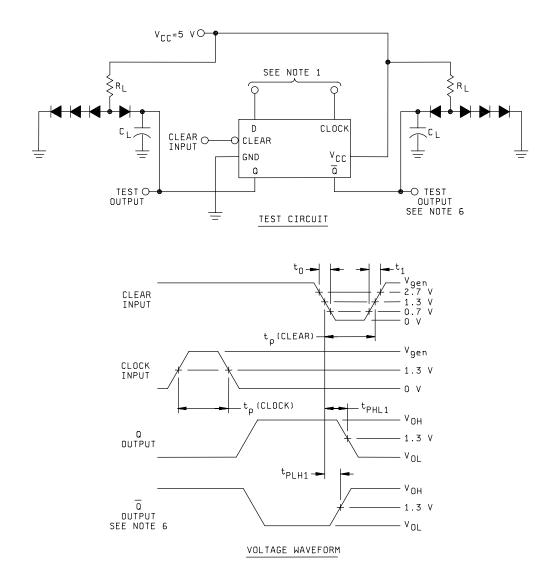
- 1. Preset inputs dominate regardless of the state of clock or J-K inputs.
- 2. Preset input pulse characteristics:  $V_{gen} = 3 \text{ V}, t_0 \le 15 \text{ ns}, t_1 \le 6 \text{ ns}, t_p \text{ (preset)} = 30 \text{ ns}, PRR \le 1 \text{ MHz}.$
- 3. All diodes are 1N3064, or equivalent.
- 4.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 5.  $R_L = 2 k\Omega \pm 5\%$ .
- 6. Clock input pulse characteristics:  $V_{gen}$  = 3 V,  $t_p(clock) \ge 25$  ns, PRR  $\le 1$  MHz.

FIGURE 11. Preset switching test circuit and waveforms for device type 04.



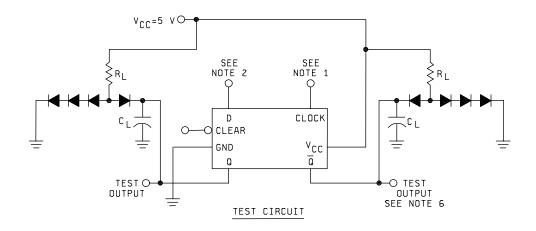
- 1. Clock input characteristics for  $t_{PLH}$ ,  $t_{PHL}$  (clock to output),  $V_{gen} = 3$  V,  $t_0 \le 6$  ns,  $t_1 \le 15$  ns, $t_p(clock) = 25$  ns, PRR  $\le 1$  MHz. When testing  $t_{MAX}$  the clock input characteristics are  $V_{gen} = 3$  V,  $t_1 = t_0 \le 6$  ns,  $t_p$  (clock)  $\le 25$  ns, and PRR = see table III.
- 2. All diodes are 1N3064, or equivalent.
- 3.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 4.  $R_L = 2 k\Omega \pm 5\%$ .

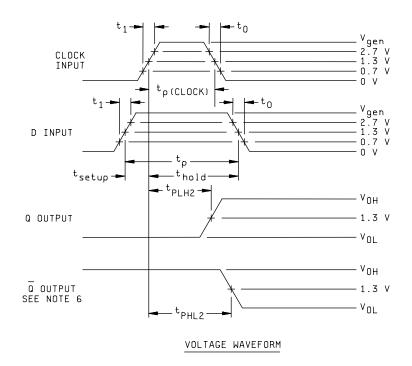
FIGURE 12. Synchronous switching test circuit for device type 04.



- 1. Clear input dominates regardless of the state of clock or D inputs.
- 2. All diodes are 1N3064, or equivalent.
- 3. Clear input pulse characteristics:  $V_{gen}$  = 3 V,  $t_0 \le 6$  ns,  $t_1 \le 15$  ns,  $t_p(clear)$  = 35 ns, PRR  $\le 1$  MHz.
- 4.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 5.  $R_L = 2 k\Omega \pm 5\%$ .
- 6.  $\overline{Q}$  output applies to device type 07 only.
- 7. Clock input pulse characteristics:  $t_p$  (clock)  $\geq$  25 ns,  $V_{gen}$  = 3 V, PRR  $\leq$  1 MHz.

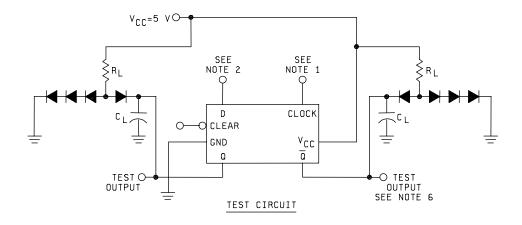
FIGURE 13. Asynchronous switching test circuit for device types 06 and 07.

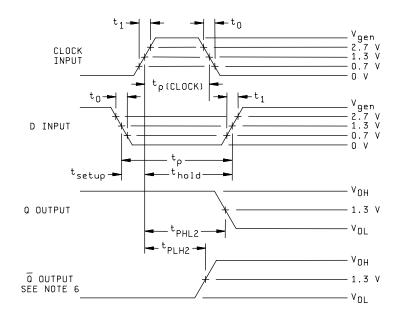




- 1. Clock input pulse has the following characteristics:  $V_{gen}$  = 3 V,  $t_1$  ≤ 15 ns,  $t_0$  ≤ 6 ns,  $t_p$  (clock) = 30 ns, and PRR ≤ 1 MHz. When testing  $f_{MAX}$ , PRR = see table III,  $t_p$  (clock) ≤ 30 ns, and  $t_0$  =  $t_1$  ≤ 6ns.
- 2. D input has the following characteristics:  $V_{gen}=3$  V,  $t_1 \le 15$  ns,  $t_0 \le 6$  ns,  $t_{setup}=20$  ns,  $t_{hold}=5$  ns,  $t_p=25$  ns, and PRR is 50% of the clock PRR. For  $f_{MAX}$ ,  $t_0=t_1 \le 6$ ns.
- 3. All diodes are 1N3064, or equivalent.
- 4.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 5.  $R_L = 2 k\Omega \pm 5\%$ .
- 6.  $\overline{Q}$  output applies to device type 07 only.

FIGURE 14. Synchronous switching test circuit (high-level data) for device types 06 and 07.

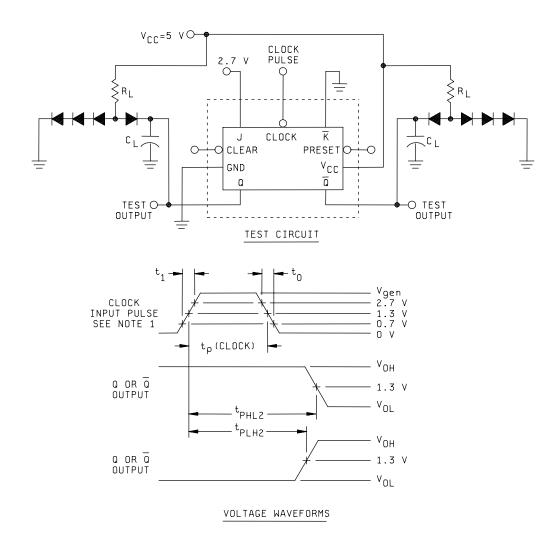




VOLTAGE WAVEFORM

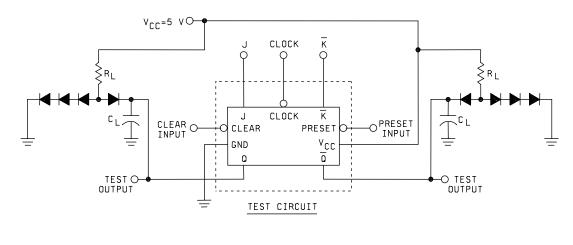
- 1. Clock input pulse has the following characteristics:  $V_{gen}$  = 3 V,  $t_1$  ≤ 15 ns,  $t_0$  ≤ 6 ns,  $t_p$  (clock) = 30 ns, and PRR ≤ 1 MHz.
- 2. D input has the following characteristics:  $V_{gen} = 3 \text{ V}$ ,  $t_1 \le 15 \text{ ns}$ ,  $t_0 \le 6 \text{ ns}$ ,  $t_{setup} = 20 \text{ ns}$ ,  $t_{hold} = 5 \text{ ns}$ ,  $t_p = 25 \text{ ns}$ , and PRR is 50% of the clock PRR.
- 3. All diodes are 1N3064, or equivalent.
- 4.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 5.  $R_L = 2 k\Omega \pm 5\%$ .
- 6.  $\overline{Q}$  output applies to device type 07 only.

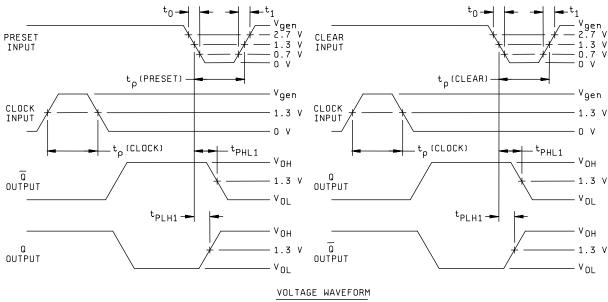
FIGURE 15. Synchronous switching test circuit (low-level data) for device types 06 and 07.



- 1. Clock input characteristics for  $t_{PLH}$ ,  $t_{PHL}$  (clock to output),  $V_{gen} = 3$  V,  $t_0 \le 6$  ns,  $t_1 \le 15$  ns,  $t_p$  (clock) = 25 ns, and PRR  $\le 1$  MHz. When testing  $t_{MAX}$ , the clock input characteristics are  $t_{gen} = 3$  V,  $t_0 = t_1 \le 6$ ns,  $t_p$  (clock)  $\le 25$  ns, and PRR = see table III,.
- 2. All diodes are 1N3064, or equivalent.
- 3.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 4.  $R_L = 2 k\Omega \pm 5\%$ .

FIGURE 16. Synchronous switching test circuit for device type 09.





- 1. Clear or preset inputs dominate regardless of the state of clock or  $J-\overline{K}$  inputs.
- 2. Clear or preset input has the following characteristics:  $V_{gen} = 3 \text{ V}$ ,  $t_1 \le 15 \text{ ns}$ ,  $t_0 \le 6 \text{ ns}$ ,  $t_p(\text{clear}) = t_p(\text{preset}) = 30 \text{ ns}$ ,  $\text{PRR} \le 1 \text{ MHz}$ , and  $Z_{out} \approx 50\Omega$ .
- 3.  $C_L = 50 \text{ pF} \pm 10\%$  (including jig and probe capacitance).
- 4.  $R_L = 2 k\Omega \pm 5\%$ .
- 5. All diodes are 1N3064, or equivalent.
- 6. When testing clear to output switching, preset input shall have a logical "1" voltage applied. When testing preset to output switching, clear input shall have a logical "1" voltage applied. (see table III).
- 7. Clock input pulse characteristics:  $t_p(clock) \ge 25$  ns,  $V_{gen} = 3$  V, PRR  $\le 1$  MHz.

FIGURE 17, Clear and preset switching test circuit and waveforms for device type 09.

## TABLE III. Group A inspection for device type 01 and 08. Terminal conditions (pins not designated may be high $\geq$ 2.0 V, low $\leq$ 0.7 V, or open).

			Cases 1/	* 2	3	4	6	8	9	10	12	13	14	16	18	19	20				
		MIL-STD-	2, X	** 18	19	6	20	13	14	12	9	8	16	10	4	3	2				
Subgroup	Symbol	883	Case	* 1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured	Lin	nits	Unit
	-	method	A,B,C,D	** 12	13	4	14	9	10	8	6	5	11	7	3	2	1	terminal			
			Test no.	CLK1	CLR1	K1	V <sub>cc</sub>	CLK2	CLR2	J2	_ Q2	Q2	K2	GND	Q1	_ Q1	J1		Min	Max	
1	V <sub>OH</sub>	3006	1	2.0 V	0.7 V	2.0 V	4.5 V							GND		4 mA	2.0 V	_ Q1	2.5		V
Tc = 25°C		"	2	<u>2</u> /	2.0 V	2.0 V	"							"		4 mA	0.7 V	_ Q1	"		"
		"	3	2/	2.0 V	0.7 V	"							"	4 mA		2.0 V	Q1	"		
		"	4				"	2.0 V	0.7 V	2.0 V	4 mA		2.0 V	"				_ Q2	"		"
		"	5				"	<u>2</u> /	2.0 V	0.7 V	4 mA		2.0 V	"				_ Q2	"		"
		"	6				"	-	"	2.0 V		4 mA	0.7 V	"				Q2	"		"
	V <sub>OL</sub>	3007	7				"	"	"	2.0 v	4 mA		0.7 V	"				_ Q2		0.4	"
		"	8				"	-	"	0.7 V		4 mA	2.0 V	"				Q2		=	"
		"	9				"	2.0 V	0.7 V	2.0 V		4 mA	2.0 V	"				Q2		"	
		"	10	2.0 V	0.7 V	2.0 V	"							"	4 mA		2.0 V	Q1		"	
		"	11	<u>2</u> /	2.0 V	2.0 V	"							"	4 mA		0.7 V	Q1		"	
		"	12	<u>2</u> /	2.0 V	0.7 V	"							"		4 mA	2.0 V	_ Q1		"	
	V <sub>IC</sub>		13	-18 mA			"							"				CLK1		-1.5	"
			14		-18 mA		"							"				CLR1			"
			15			-18mA	"							"				K1		"	-
			16				"	-18mA						"				CLK2		=	"
			17				"		-18mA					"				CLR2		=	"
			18				"			-18mA				"				J2		=	"
			19				"						-18mA					K2		-	"
			20				"							"			-18mA	J1		"	"
	I <sub>IL1</sub>	3009	21	<u>3</u> /	4.5 V	0.4 V	5.5 V							"			4.5 V	K1	4/	4/	mΑ
		"	22	4.5 V	<u>3</u> /	4.5 V	"							"			0.4 V	J1	"	"	"
		"	23				"	4.5 V	<u>3</u> /	0.4 V			4.5 V	"				J2	"	"	"
		"	24				"	<u>3</u> /	4.5 V	4.5 V			0.4 V	ı				K2	=	"	"
	I <sub>IL3</sub>	"	25	0.4 V	<u>3</u> /	4.5 V	"							"			4.5 V	CLK1	=	"	"
		"	26				"	0.4 V	<u>3</u> /	4.5 V			4.5 V	"				CLK2	•	"	"
	$I_{1L4}$	"	27	4.5 V	0.4 V	4.5 V	"							"			4.5 V	CLR1	•	"	"
			28				"	4.5 V	0.4 V	4.5 V			4.5 V	"				CLR2	"	"	
	I <sub>IH1</sub>	3010	29	GND	GND	2.7 V	"							"			4.5 V	K1		20	μΑ
			30	GND	GND	4.5 V	"										2.7 V	J1		"	
			31				- "	GND	GND	2.7 V			4.5 V	- "				J2		"	- "
	L	"	32					GND	GND	4.5 V			2.7 V					K2			
	I <sub>IH2</sub>		33				"	GND	GND	4.5 V			5.5 V					K2		100	
			34	01:-	01:-			GND	GND	5.5 V			4.5 V	"		<u> </u>	4.5	J2			
		l ".	35	GND	GND	5.5 V										<u> </u>	4.5 V	K1			
	<u> </u>		36	GND	GND	4.5 V	- "									<u> </u>	5.5 V	J1		"	
	I <sub>IH5</sub>	"	37	GND	2.7 V	4.5 V	"	0115	0 = 1 :	0115			4 = 3 :			ļ	GND	CLR1		60	
	L.		38				"	GND	2.7 V	GND			4.5 V			ļ		CLR2		60	
	I <sub>IH6</sub>	l ".	39	0115		4 = 3 :		GND	5.5 V	GND			4.5 V			<del>                                     </del>	0115	CLR2		300	
			40	GND	5.5 V	4.5 V											GND	CLR1		300	

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See footnotes at end of device types 01 and 08.

TABLE III. <u>Group A inspection for device type 01 and 08</u> – Continued. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

						ninai cor						≥ 2.0 V, I									
			Cases <u>1</u> /	* 2	3	4	6	8	9	10	12	13	14	16	18	19	20				İ
		MIL-STD-	2, X	** 18	19	6	20	13	14	12	9	8	16	10	4	3	2				İ
Subgroup	Symbol	883	Case	* 1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured	Lim	its	Unit
		method	A,B,C,D	** 12	13	4	14	9	10	8	6	5	11	7	3	2	1	terminal			1
			Test no.	CLK1	CLR1	K1	V <sub>cc</sub>	CLK2	CLR2	J2	_ Q2	Q2	K2	GND	Q1	_ Q1	J1		Min	Max	
1	I <sub>IH7</sub>	3010	41	2.7 V	GND	GND	5.5 V							GND			GND	CLK1		80	μΑ
$Tc = 25^{\circ}C$		"	42				"	2.7 V	GND	GND			GND					CLK2		80	
	I <sub>IH8</sub>		43				"	5.5 V	GND	GND			GND	"				CLK2		400	
		"	44	5.5 V	GND	GND	"							"			GND	CLK1		400	
	los	3011	45	GND	GND	4.5 V	"							"		GND	GND	Q1	-15	-100	mA
		"	46	<u>2</u> /	4.5 V	GND	"							=	2.25 V	GND	4.5 V	Q1	<u>5</u> /	<u>5</u> /	"
		"	47				"	GND	GND	GND	GND		4.5 V	"				_ Q2	-15	-100	"
		"	48				"	2/	4.5 V	4.5 V	GND	2.25 V	GND	"				Q2	5/	<u>5</u> /	"
	I <sub>C C</sub>	3005	49	GND	GND	GND	"	GND	GND	GND			GND	"			GND	Vcc		8.0	"
	I <sub>C</sub> C	3005	50	2/	5.5 V	GND	"	2/	5.5 V	5.5 V			GND	"			5.5 V	Vcc		8.0	"
2		sts, terminal o					cept T <sub>C</sub> =	+125° C.			omitted.	L		U							
3		sts, terminal o																			
7	Truth	3014	51	В	B B	В	4.5 V	В	B	В	Н	L	В	GND	L	Н	Α	All		See <u>8</u> /	
<u>6</u> /, <u>7</u> /	table	"	52	A	"	"	T.0 V	"	"	"	"	-	=	0140		"	"	outputs		"	
<u>o</u> , <u>n</u>	tests		53	В			"	"	"	"	"	"		"	"	"	"	"		"	
	16212		54	В	Α		"	"	"	"	"	"								,	
			55	A	" "		"	"	"	"	"	"		"		"		"	"		
					"		"	,,	"	" "		,					-	"	"		
			56	В	"			,	"	"	"	"			H	L "		"			
			57	В	"	A	"	"	-	"		"				"	В	"		- "	
			58	A B	"			,	"	"	"	"			1			"		-	
			59	"			"	"	"	"		"	-		<u>L</u>	H	- "	"			
			60	"	В	В	"	"				"				"		"		-	
			61	"			"		A	A		,,				"	- "				
			62	"	-	- "	"	A	"	- "			"	"	- :	"	- "				
			63	"	"	"		В	"		L "	H			"	"	"	"			
			64				"	В		В		"	A				- "	"			
			65	"	"	"	"	Α	"	"	"	"	-	"	"	"				"	
		"	66	"	"	"	"	В	"	"	Н	L	"	"	"	"	"	"		"	
		"	67	"	"	"	"	"	В	"	"	"	В	"	-	"	"	"		"	
		"	68	"	Α	"	"	"	Α	"	"	"			=	"	"	"		"	
		"	69	Α	"	"	"	Α	"	"	"	"	"	"	"	"	"	"		"	
			70	В	"	"	"	В	"	"	"	"	"	"	=	"	"	"		"	
		"	71	В	"	Α	"	В	"	Α	"	"	Α	"	"	"	Α	"		"	
		"	72 <u>9</u> /	Α	"	"	"	Α	"	"	"	"	"	"	"	"	"	"		"	
		"	73	В	"	"	"	В	"	"	L	Н	"	"	Н	L	"	"		"	
		"	74	В	"	В	"	В	"	В	"	"	В	"	"	"	В	"		"	
		"	75	Α	"	"	"	Α	"	"	"	"		-	=	"	"	"		"	·
		"	76	В	"	"	"	В	"	"	"	"	"	"	"	"	"	"		"	
		"	77	В	"	Α	"	В	"	Α	"	"	Α	-	=	"	Α	"		"	
		"	78 9/	Α	"	"	"	Α	"	"	"	"	"	"	"	"	"	"		"	
		"	79	В	"	"	"	В	"	"	Н	L		"	L	Н	"	"		"	
8 <u>6</u> /, <u>7</u> /			T <sub>C</sub> = +125°		EE0 C	1								U	_			1			

See footnotes at end of device types 01 and 08.

35

MHz

ns

30

32

40

32

42

5

5

5

2.7 V

2.7 V

OUT

14

16

16

10

18

4

20

2

19

3

OUT

OUT

OUT

2.7 V

2.7 V

2.7 V

CLK1 to Q1

CLK1 to Q1

CLK1 to Q1

CLK2 to Q2 CLK2 to Q2

13

8

12

9

TABLE III. Group A inspection for device type 01 and 08 – Continued. Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open). 10

12

6

20

8

13

IN

IN

2.7 V

2.7 V

2.7 V

2.7 V

OUT

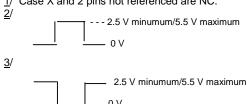
9

14

*	Terminal	numbers	for	device	type 0	1

<sup>\*\*</sup> Terminal numbers for device type 08.

<sup>1/</sup> Case X and 2 pins not referenced are NC.



Cases 1/

2, X

Case

A,B,C,D

Test no.

80

81

82

83

85

86

87

88

90

91

92

93

94

95

96 - 99

102 - 103

104 - 107

108 - 111

MIL-STD-

883

method

Fig. 4

3003

Fig.4

3003

Fig.5

3003

Fig.5

Fig. 4

3003

Fig. 4 3003

Fig. 4

3003

Fig. 5 3003

Fig. 5

Symbol

<u>10</u>/

t<sub>PLH1</sub>

t<sub>PHL1</sub>

 $t_{PLH2}$ 

t<sub>PHL2</sub>

t<sub>PLH1</sub>

t<sub>PHL1</sub>

t<sub>PLH2</sub>

t<sub>PHL2</sub>

Subgroup

Tc = 25°C

10

Tc = +125°C

2

18

1

12

CLK1

IN

IN

IN

IN

Same tests, terminal conditions, and limits as for subgroup 10, except  $T_C = -55^{\circ}C$ 

19

2.7 V

2.7 V

100 - 101 Same tests and terminal conditions as for subgroup 9, except T<sub>C</sub> = +125°C

6

# TABLE III. Group A inspection for device type 01 and 08 – Continued. Terminal conditions (pins not designated may be high $\geq$ 2.0 V, low $\leq$ 0.7 V, or open).

### $\underline{4}$ / $I_{IL}$ limits in mA are as follows:

		Min/	Max limits for	CKT	
I <sub>IL1</sub>	Α	В	С	D	E
	075/250	03/30	11/25	12/36	12/36

		Min/	Max limits for	CKT	
I <sub>IL3</sub>	Α	В	С	D	E
	15/60	06/60	15/56	29/72	24/72

		Min/	Max limits for	CKT	
I <sub>IL4</sub>	Α	В	С	D	E
	16/70	06/70	29/65	20/80	12/72

 $\underline{5}$ /  $I_{OS}$  limits are as follows:

37

Test nos. 46 and 48: CKT's A, B, C - -7.5/-50 CKT D - -15/-100

- $\underline{6}$ / Input voltages shown are A = 2.0 volts minimum and B = 0.7 volts maximum.
- 7/ Tests shall be performed in sequence, attributes data only.
- 8/ Output voltages shall be H ≥ 1.5 V and L < 1.5 V.
- 9/ These tests may be performed as shown in table III or alternately as follows:

Test no.	CLK1	CLR1	K1	V <sub>CC</sub>	CLK2	CLR2	J2	_ Q2	Q2	K2	GND	Q1	Q1	J1
72A	Α	Α	Α	4.5 V	В	Α	Α	Н	L	Α	GND	L	Н	Α
72B	В	"	"	"	В	"	"	Н	L	"	"	Н	L	"
72C	В	"	"	"	Α	"	"	Н	L	"	"	Н	L	"
78A	Α	"	"	"	В	"	II .	L	Н	"	"	Н	L	"
78B	В	"	"	"	В	"	II .	Ш	Н	"	II .	L	Н	=
78C	В	"	"	"	Α	"	"	L	Н	"	"	L	Н	"

10/ f<sub>MAX</sub> minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.

TABLE III. Group A inspection for device type 02. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

					rei	minai co	nailions	(pins no	caesigna					7 V, or op							
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
Subgroup	Symbol	883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Lim	nits	Unit
			Test no.	CLR1	D1	CLK1	PR1	Q1	- Q1	GND	_ Q2	Q2	PR2	CLK2	D2	CLR2	V <sub>cc</sub>		Min	Max	
1	V <sub>OH</sub>	3006	1	0.7 V	2.0 V	GND	2.0 V		4 mA	GND							4.5 V	_ Q1	2.5		V
Tc = 25°C		"	2	2.0 V	"	GND	0.7 V	4 mA		"							"	Q1	-		=
		"	3	"	"	2/	2.0 V	4 mA		"							"	Q1	-		=
		"	4	"	0.7 V	<u>2</u> /	2.0 V		4 mA	"							"	_ Q1			"
			5							"		4 mA	0.7 V	GND	2.0 V	2.0 V	"	Q2	"		=
		"	6							"	4 mA		2.0 V	GND	2.0 V	0.7 V	"	Q2	"		"
		"	7							"	4 mA		"	<u>2</u> /	0.7 V	2.0 V	"		"		"
		"	8							"		4 mA	"	2/	2.0 V	2.0 V	"	Q2	"		=
	V <sub>OL</sub>	3007	9	2.0 V	0.7 V	2/	2.0 V	4 mA		"				_=	2.0 1	2.0 .	"	Q1		0.4	"
	- 01	"	10	"	2.0 V	2/	2.0 V		4 mA	"							"	Q1		"	"
		"	11	"	"	GND	0.7 V		4 mA	"							"	Q1		"	"
			12	0.7 V	"	GND	2.0 V	4 mA		"							-	Q1			
			13	0.7 V		GIND	2.0 V	4 IIIA		"		4 mA	2.0 V	<u>2</u> /	0.7 V	2.0 V		Q2		"	
		"	14							"	4 mA	4111/4	2.0 V	<u>2</u> /	2.0 V	2.0 V	"	Q2		"	
		"	15							"	4 mA		0.7 V	GND	"	"	"	Q2		"	"
		"	16							"		4 mA	2.0 V	GND	"	0.7 V	"	Q2		"	
	V <sub>IC</sub>		17	-18 mA						"		7111/1	2.0 V	OND		0.7 V	"	CLR1		-1.5	=
	• 10		18	10 11	-18 mA					"							"	D1		"	"
			19			-18 mA				"							"	CLK1		"	=
			20				-18 mA			"							"	PR1		"	=
			21							"			-18 mA				"	PR2		"	"
			22							"				-18 mA			"	CLK2		"	=
			23												-18 mA			D2			=
			24							"						-18 mA	"	CLR2		"	-
	I <sub>IL2</sub>	3009	25	4.5 V	0.4 V	4.5 V	GND			"							5.5 V	D1	<u>3</u> /	<u>3</u> /	mΑ
		=	26							"			GND	4.5 V	0.4 V	4.5 V	"	D2	"	"	-
	I <sub>IL4</sub>		27	4.5 V	GND	0.4 V	GND			"							"	CLK1	"	"	"
1			28	GND	GND	GND	0.4 V			"			0.417	ONE	0115	0115	- "	PR1	"	"	"
1		"	29							- "			0.4 V	GND	GND	GND		PR2	- "		"
L	l		30										GND	0.4 V	GND	4.5 V	l	CLK2			

See footnotes at end of device type 02.

TABLE III. <u>Group A inspection for device type 02</u> - Continued.

Terminal conditions (pins not designated may be high > 2.0 V, low < 0.7 V, or open).

					Ter	minal co	nditions	(pins not	: designa	ated may	, be high	≥ 2.0 V,	$low \leq 0$ .	7 V, or o <sub>l</sub>	pen).						
			Cases 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
		MIL-STD-	2, X																		
Subgroup	Symbol	883	Cases	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured	Lim	its	Unit
		method	A,B,C,D															terminal			
			Test no.	CLR1	D1	CLK1	PR1	Q1	_ Q1	GND	_ Q2	Q2	PR2	CLK2	D2	CLR2	V <sub>CC</sub>		Min	Max	
1	I <sub>IL5</sub>	3009	31	0.4 V	4.5 V	4.5 V	GND			GND							5.5 V	CLR1	3/	3/	mA
Tc = 25°C	-	"	32							"			GND	4.5 V	4.5 V	0.4 V	"	CLR2	3/	3/	mA
	I <sub>IH1</sub>	3010	33	GND	2.7 V	4.5 V	4.5 V			"							"	D1		20	μΑ
		"	34							"			4.5 V	4.5 V	2.7 V	GND	"	D2		20	"
	I <sub>IH2</sub>		35							"			4.5 V	4.5 V	5.5 V	GND	"	D2		100	"
		=	36	GND	5.5 V	4.5 V	4.5 V			"							"	D1		100	"
	I <sub>IH3</sub>		37	GND	4.5 V	2.7 V	4.5 V			"							"	CLK1		40	"
		"	38	4.5 V	4.5 V	<u>4</u> /	2.7 V			"							"	PR1			"
		"	39							"			2.7 V	<u>4</u> /	4.5 V	4.5 V	"	PR2		"	"
			40							"			4.5 V	2.7 V	4.5 V	GND	"	CLK2		"	"
	$I_{1H4}$	"	41							"			4.5 V	5.5 V	4.5 V	GND	"	CLK2		200	"
		"	42							"			5.5 V	<u>4</u> /	4.5 V	4.5 V	"	PR2		"	"
		"	43	4.5 V	4.5 V	<u>4</u> /	5.5 V			"							"	PR1		"	"
			44	GND	4.5 V	5.5 V	4.5 V			"							"	CLK1		"	"
	I <sub>IH5</sub>	"	45	2.7 V	GND	<u>4</u> /	4.5 V			"							"	CLR1		60	
			46							"			4.5 V	<u>4</u> /	GND	2.7 V	"	CLR2		60	"
	I <sub>IH6</sub>		47							"			4.5 V	<u>4</u> /	GND	5.5 V	"	CLR2		300	"
			48	5.5 V	GND	<u>4</u> /	4.5 V			"							"	CLR1		300	"
	los	3011	49	GND					GND	"							"	_ Q1	-15	-100	mA
		"	50				GND	GND		"							"	Q1	"		"
		"	51							"		GND	GND				"	Q2	"		"
		"	52							"	GND					GND	"	_ Q2	"	"	"
	Icc	3005	53	5.5 V	GND	GND	GND			"			GND	GND	GND	5.5 V	"	V <sub>CC</sub>		8.0	"
		3005	54	GND	GND	GND	5.5 V			"			5.5 V	GND	GND	GND	"	V <sub>CC</sub>		8.0	"
2	Same tes	sts, terminal o	conditions, a	and limits a	s for subg	group 1, e	xcept T <sub>C</sub> =	+125°C	and V <sub>IC</sub> te	sts are or	nitted.									•	
	Same tes	sts, terminal o		ınd limits a	s for subg	group 1, e	xcept T <sub>C</sub> =	-55°C ar	d V <sub>IC</sub> test		tted.										
7 <u>5</u> /, <u>6</u> /	Truth	3014	55	В	В	В	В	Н	Н	GND	Н	Н	В	В	В	В	4.5 V	All outputs		See <u>7</u> /	
$Tc = 25^{\circ}C$	table	"	56	В	"	"	Α	L		"	"	L	Α	-	"	В	"	"		"	
	tests	"	57	Α	"	"	Α	L	=	"	"	L	Α	=	"	Α	"	"		"	
		"	58	"	"	"	В	Н	L	"	L	Н	В	"	"	"	"	"		"	
		"	59	"	"	Α	"	=	L	"	L	"	"	Α	"	"	"	"		"	
		"	60	В	"	=	"	=	Н	"	Н	"	"	"	"	В	"	"		"	
		"	61	В	Α	"	"	"	Н	"	Н	"	"	"	Α	В	"	"		"	

See footnotes at end of device type 02.

TABLE III. <u>Group A inspection for device type 02</u> - Continued. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

					ı eı	rminai co	naitions	(pins no	t designa	ated may	/ be nign	≥ 2.0 V,	$low \le 0$ .	7 V, or o <sub>l</sub>	pen).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
Subgroup	Symbol		Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Liı	mits	Unit
		metriod	Test no.	CLR1	D1	CLK1	PR1	Q1	_ Q1	GND	_ Q2	Q2	PR2	CLK2	D2	CLR2	V <sub>cc</sub>	tomina	Min	Max	
7 <u>5</u> /, <u>6</u> /	Truth	3014	62	В	Α	Α	Α	L	Н	GND	Н	L	Α	Α	Α	В	4.5 V	All outputs		See 7/	
Tc = 25°C	table	"	63	Α	"	"	Α	L	Н	"	Н	L	Α	"	"	Α	"	"		"	
	tests	"	64	"	"	"	В	Н	L	"	L	Н	В	"	"	"	"	"		"	
		"	65	"	"	"	Α	"	"	"	"	"	Α	"	"	"	"	"		"	
		"	66	"	=	В	"	=	"	"	"	"	"	В	"	"	"	"		"	
		"	67	"	В	В	"	"	"	"	"	"	"	В	В	"	"	"		"	
		"	68	"	-	Α	"	L	Н	"	Н	L	"	Α	"	"	"	"		"	
			69		- "	"	В	Н	L	- "	L	Н	В	-		-	- "	"			
			70	В	A	"	- "		H		H		- "	- "	A	В	-:-			- "	
			71		В				"	-	"				В						
			72 73	Α	,		A	_ <u>_</u> _	"		"	L "	A		"	Α					
		"	74	- A	Α	В	"	"	"		"	"	"	В	Α	- A		"		-	
			75	"	"	A	"	Н	L	"	L	Н	"	A	"	"	"	"		"	
		"	76	"	"	"	В	-	"	"	-	"	В	"	"	"	"	"		"	
		"	77	"	"	"	A	"	"	"	"	"	A	"	"	"		"		"	
		"	78	В	"	"	"	L	Н	"	Н	L	"	"	"	В	"	"		"	
		"	79	Α		"	"	L	Н	"	Н	L	"	"	"	Α	"	"		"	
		"	80	"	В	-	В	Н	L	"	L	Н	В	-	В	"	"	"		"	
		"	81	"	В	"	Α	Н	L	"	L	Н	Α	"	В	"	"	"		"	
8 <u>4</u> /, <u>5</u> /	Repeat s	ubgroup 7 at	$T_{\rm C} = +125^{\circ}$	C and $T_c$ =	= -55°C																
9	f <sub>MAX</sub>	Fig. 8	82	2.7 V	IN	IN	2.7 V	OUT		GND							5.0 V	Q1	20		MHz
Tc = 25°C		<u>8</u> /	83	2.7 V	IN	IN	2.7 V		OUT									_ Q1			
			84							"	OUT		2.7 V	IN	IN	2.7 V		_ Q2			
		"	85							"		OUT	2.7 V	IN	IN	2.7 V	"	Q2	"		"
	t <sub>PLH1</sub>	3003	86							- "	OUT	OUT	IN			IN	-:-	PR2 to Q2	5	30	ns
		Fig. 6	87								OUT		IN			IN		CLR2 to Q2			
		"	88	IN			IN		OUT									CLR1 to Q1	. "	"	. "
		"	89	IN			IN	OUT		"								PR1 TO Q1	"	"	"
	t <sub>PHL1</sub>	"	90	IN			IN	OUT		"							"	CLR1 to Q1	"	46	"
		"	91	IN			IN		OUT	"							"	PR1 to Q1	"	"	"
		"	92							"	OUT		IN			IN	"	PR2 to Q2	"	"	"
		"	93							"		OUT	IN			IN	"	CLR2 to Q2	"	"	"
	t <sub>PLH2</sub>	3003 Fig. 7	94							"		OUT	2.7 V	IN	IN	2.7 V	"	CLK2 to Q2	"	30	"
		3003 Fig. 8	95							"	OUT		2.7 V	IN	IN	2.7 V	"	CLK2 to Q2	"	"	"
		3003 Fig. 7	96	2.7 V	IN	IN	2.7 V	OUT		"							"	CLK1 to Q1	"	"	"
		3003 Fig. 8	97	2.7 V	IN	IN	2.7 V		OUT	"							"	CLK1 to Q1	"	"	"
	t <sub>PHL2</sub>	3003 Fig. 7	98	2.7 V	IN	IN	2.7 V		OUT	"							"	CLK1 to Q1	"	46	"
		3003 Fig. 8	99	2.7 V	IN	IN	2.7 V	OUT		"							"	CLK1 to Q1	"	"	"
		3003 Fig. 7	100							"	OUT		2.7 V	IN	IN	2.7 V	"	CLK2 to Q2	"	"	"
1		3003 Fig. 8	101							"		OUT	2.7 V	IN	IN	2.7 V	"	CLK2 to Q2	"	"	"

See footnotes at end of device type 02.

TABLE III. Group A inspection for device type 02 - Continued.

Terminal conditions (pins not designated may be high > 2.0 V. low < 0.7 V. or open).

			Cases 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
		MIL-STD-	2, X																		
Subgroup	Symbol	883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Lii	mits	Unit
			Test no.	CLR1	D1	CLK1	PR1	Q1	_ Q1	GND	_ Q2	Q2	PR2	CLK2	D2	CLR2	V <sub>CC</sub>		Min	Max	
10	f <sub>MAX</sub> 8/	Fig. 8	102-105		•			•					•						20		MHz
	t <sub>PLH1</sub>	3003 Fig.6	106-109																5	39	ns
	t <sub>PHL1</sub>	3003 Fig. 6	110-113																"	59	"
		3003 Fig. 7	114																"	39	"
		3003 Fig. 8		Same tes	ts and ter	minal cond	ditions as	for subgro	oup 9, exc	$ept T_C = +$	+125°C									"	"
		3003 Fig. 7	116																	"	"
		3003 Fig. 8																	- "		<del>- "-</del>
		3003 Fig. 7	118																	59	<del>- "</del>
		3003 Fig. 8																			<del>-</del>
		3003 Fig. 7	120																- "		<del>"</del>
11		3003 Fig. 8 sts, terminal of		L																	<u> </u>

1/ Case X and 2 pins not referenced are NC.

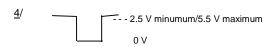
- - - 2.5 V minumum/5.5 V maximum

3/ I<sub>IL</sub> limits in mA are as follows:

			Min/Ma	x limits for CKT		
I <sub>IL2</sub>	Α	В	С	D	Е	F
	075/250	030/300	095/210	097/207	135/370	-160/400

			Min/Ma	x limits for CKT		
I <sub>IL4</sub>	Α	В	С	D	Е	F
	150/500 for tests 27, 30 200/800 for tests 28, 29	060/700	160/400 for tests 27, 30 350/760 for tests 28, 29	160/400 for tests 27, 30 355/759 for tests 28, 29	120/360 for tests 27, 30 280/760 for tests 28, 29	320/800 (All)

			Min/Ma:	x limits for CKT		
I <sub>IL5</sub>	Α	В	С	D	E	F
	200/800	060/700	350/760	480/-1.200	280/760	480/-1.200



- $\underline{5}/$  Input voltages shown are A = 2.0 volts minimum and B = 0.7 volt maximum.  $\underline{6}/$  Tests shall be performed in sequence, attributes data only.

- Output voltages shall be  $H \ge 1.5$  V and L < 1.5 V. 8/  $f_{MAX}$  minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.

TABLE III. Group A inspection for device type 04. Terminal conditions (pins not designated may be high  $\geq 2.0 \text{ V}$ , low  $\leq 0.7 \text{ V}$ , or open).

							naitions				be high										
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
Subgroup	Symbol	883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Lin	nits	Unit
			Test no.	CLK1	K1	J1	PR1	Q1	_ Q1	GND	_ Q2	Q2	PR2	J2	K2	CLK2	V <sub>cc</sub>	1	Min	Max	
1	V <sub>OH</sub>	3006	1	2.0 V	2.0 V	2.0 V	0.7 V	4 mA		GND							4.5 V	Q1	2.5		V
Tc = 25°C		"	2	<u>2</u> /	2.0 V	0.7 V	2.0 V		4 mA	"							"	_ Q1	"		"
		"	3	2/	0.7 V	2.0 V	2.0 V	4 mA		"							"	Q1	"		"
		"	4							"	4 mA		2.0 V	0.7 V	2.0 V	<u>2</u> /	"	_ Q2	"		"
		"	5							"		4 mA	2.0 V	2.0 V	0.7 V	2/	"	Q2			"
			6							"		4 mA	0.7 V	"	2.0 V	2.0 V	"	Q2			=
	V <sub>OL</sub>	3007	7							"	4 mA		0.7 V	"	2.0 V	2.0 V	"	_ Q2		0.4	"
		"	8							"	4 mA		2.0 V	"	0.7 V	<u>2</u> /	"	_ Q2		"	"
		"	9							"		4 mA	2.0 V	0.7 V	2.0 V	<u>2</u> /	"	Q2		"	"
		"	10	2.0 V	2.0 V	2.0 V	0.7 V		4 mA	"							"	Q1		"	"
		"	11	<u>2</u> /	0.7 V	2.0 V	2.0 V		4 mA	"							"	_ Q1		"	"
		"	12	2/	2.0 V	0.7 V	2.0 V	4 mA		"							"	Q1		"	"
	V <sub>IC</sub>		13	-18 mA		• • • • • • • • • • • • • • • • • • • •				"							"	CLK1		-1.5	"
	10		14	_	-18 mA					"							"	K1		"	"
			15			-18 mA				"							"	J1		"	=
			16				-18 mA			ı							"	PR1		"	=
			17							"			-18 mA				"	PR2		"	"
			18							-				-18 mA			"	J2		"	=
			19							"					-18 mA		"	K2		"	"
			20				- /			"						-18 mA	"	CLK2		"	
	I <sub>IL1</sub>	3009	21	4.5 V	0.4 V	GND	<u>3</u> /			- "							5.5 V	K1	<u>4</u> /	<u>4</u> /	mA "
			22 23	<u>3</u> /	4.5 V	0.4 V	4.5 V						3/	GND	0.4 V	4.5 V		J2 K2		-	-
			23							"			4.5 V	0.4 V	4.5 V	4.5 V		J2			
	I <sub>IL3</sub>	"	25							"			3/	4.5 V	4.5 V	0.4 V		CLK2	"		
	IIL3		26	0.4 V	4.5 V	4.5 V	3/			"			<u> </u>	4.5 V	4.5 V	0.4 V		CLK1	"	"	"
	I <sub>IL4</sub>	"	27	4.5 V	4.5 V	4.5 V	0.4 V			"								PR1	"	"	
	·1L4		28		1.0 1		01.1			"			0.4 V	4.5 V	4.5 V	4.5 V	"	PR2	"	"	"
	I <sub>IH1</sub>	3010	29	GND	2.7 V	GND	GND			"							"	K1		20	μА
		"	30	2/	GND	2.7 V	4.5 V			"							"	J1		"	"
		"	31	_						"			4.5 V	2.7 V	GND	2/	"	J2		"	"
			32							"			GND	GND	2.7 V	GND	"	K2		"	=
	I <sub>IH2</sub>	"	33							"			GND	GND	5.5 V	GND	"	K2		100	-
		"	34							"			4.5 V	5.5 V	GND	<u>2</u> /	"	J2		"	=
		"	35	<u>2</u> /	GND	5.5 V	4.5 V			"							"	J1		"	"
		"	36	GND	5.5 V	GND	GND			II .							"	K1		"	

See footnotes at end of device type 04.

TABLE III. Group A inspection for device type 04 - Continued. Terminal conditions (pins not designated may be high  $\geq 2.0 \text{ V}$ , low  $\leq 0.7 \text{ V}$ , or open).

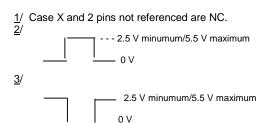
					lei	rminal co	nditions	(pins no	t designa	ated may	be high	≥ 2.0 V,	$low \leq 0$ .	/ V, or o	pen).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
Subgroup	Symbol	883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Lim	nits	Unit
			Test no.	CLK1	K1	J1	PR1	Q1	_ Q1	GND	_ Q2	Q2	PR2	J2	K2	CLK2	V <sub>CC</sub>		Min	Max	
1	I <sub>IH5</sub>	3010	37	GND	GND	4.5 V	2.7 V	<u>5</u> /		GND							5.5 V	PR1		60	μA
Tc = 25°C		"	38							"		<u>5</u> /	2.7 V	4.5 V	GND	GND	"	PR2		60	- "
	I <sub>IH6</sub>		39							"		<u>5</u> /	5.5 V	4.5 V	GND	GND	"	PR2		300	"
		"	40	GND	GND	4.5 V	5.5 V	<u>5</u> /		"							"	PR1		300	"
	I <sub>IH7</sub>	"	41	2.7 V	GND	GND	GND	_		"							"	CLK1		80	"
		"	42		_	_	_			"			GND	GND	GND	2.7 V	"	CLK2		80	"
	I <sub>IH8</sub>	-	43							"			GND	GND	GND	5.5 V	"	CLK2		400	"
	1110		44	5.5 V	GND	GND	GND			"			_				"	CLK1		400	"
	los	3011	45				GND	GND		"							"	Q1	-15	-100	mA
	-00	"	46	<u>2</u> /	4.5 V	GND	4.5 V	GND	GND <u>6</u> /	"							"	Q1	<u>6</u> /	<u>6</u> /	"
			47							"		GND	GND				"	Q2	-15	-100	"
		н	48							"	GND <u>6</u> /	GND	4.5 V	GND	4.5 V	<u>2</u> /	"	Q2	<u>6</u> /	<u>6</u> /	II .
	I <sub>CC</sub>	3005	49	2/	5.5 V	GND	5.5 V			"			5.5 V	GND	5.5 V	2/	"	V <sub>CC</sub>		8.0	-
	-00	3005	50	5.5 V	5.5 V	5.5 V	GND			"			GND	5.5 V	5.5 V	5.5 V	"	V <sub>CC</sub>		8.0	-
2	Same tes	sts, terminal						+125°C	and Vic te	ests are o	mitted						1	100	1		
3	Same tes	sts, terminal	conditions a	and limits a	s for subc	roup 1, e	xcent To =	55°C ar	nd V <sub>10</sub> tes	ts are om	itted										
7 <u>7</u> /, <u>8</u> /	Truth	3014	51	В	A	В	В	H	1 1	GND	L	Н	В	В	В	В	4.5 V	All		See <u>9</u> /	
. <u>., ., .</u>	table	"	52	A	"	"	"		-	"	-		"	-	"	"	1.0 v	outputs		"	
	tests		53	В	"	"	"		"	"	"	"	"			"		"			
	10313	"	54	В	"		Α		"	"	"	"					"	"			
			55	A	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
			56	В	"	"	"	-	Н	"	"	"	"			"					
			57	В	В	Α	"	-	"		"	"	"			"					
			58	A	"	"	"		"		"	"	"			"					
			59	В	"	"	"	Н	L	"	"	"	"	"	"	"	"	"			
			60	"	"	В	В	- ''	-		"	"	"		Α	"					
			61	"	"	-	"		"		"	"	Α		"	"					
			62	"	"	"	"		"		"	"	"			Α					
			63	"	"	"	"	"	"		Н	L	"		"	В	"	"			
			64	"	"	"	"	"	"		"	"	"	Α	В	В	"	"			
			65	"	"	"	"	"	"	"	"	"	"		"	A	"	"		"	
			66	"	"	"	"	"	"	"	L	Н	"	"	"	В	"	"			
			67	"	"	"	"	"	"	"	-	-;;	В	В	"	"	"	"			
			68	"	"	"	Α		"		"	"	A	-		"					
			69	Α	"	"	"	"	"	"	"	"	"	"	"	Α	"	"			
			70	В	"	"	"	"	"	"	"	"	"	"	"	В	"	"			
			71	В	Α	Α	"	"	"	"	"	"	"	Α	Α	В	"	"		"	
			72	A	"	"	"	"	"	"	"	"	"	"	"	A	"	"		"	
			73	В	"	"	"		Н	"	Н	L	"	"		В	"	"		"	
			74	В	В	В	"	"	"		"	<u> </u>	"	В	В	В	"	"		-	
			75	A	"	D	"	"	"	"	"	"	"	D	D	A	"	"		"	
		"	76	В	"				"	"	"	"				В		"	1		
		"	77	В	Α	Α			"	"	"	"		Α	A	В		"	-		
			78		A	A	-		-	-	"	"	-	A	A		-	"	<b></b>	"	
		"	78	A B	"			Н	-	"	1	Н				A B	-	"	1		
0.5.7/	D					L	L	17		<u> </u>	_ L	11	L	<u> </u>	l	0	<u> </u>	l	<u> </u>		
8 <u>3</u> , <u>//</u>	kepeat s	ubgroup 7 at	$I_{\rm C} = +125^{\circ}$	∪ and I <sub>C</sub> =	= -55°U.																

See footnotes at end of device type 04.

TABLE III. <u>Group A inspection for device type 04</u> - Continued.

Terminal conditions (pins not designated may be high > 2.0 V, low < 0.7 V, or open).

					1 61	IIIIIIai co	Hallions	(piris rio	i uesigna	aleu may	be nign	≥ 2.0 v,	10W ≤ 0.	7 V, or o							
			Cases <u>1</u> /	2	3	4	6	8	9	10	12	13	14	16	18	19	20				l
		MIL-STD-	2, X																		l
Subgroup	Symbol	883	Cases	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured	Lim	nits	Unit
		method	A,B,C,D															terminal			1
			Test no.	CLK1	K1	J1	PR1	Q1	_ Q1	GND	_ Q2	Q2	PR2	J2	K2	CLK2	V <sub>cc</sub>		Min	Max	l
									QI		QZ										<del></del>
9	f <sub>MAX</sub>	Fig. 11	80	IN	2.7 V	2.7 V	2.7 V	OUT		GND							5.0 V	Q1	25		MHz
$Tc = 25^{\circ}C$	<u>8</u> /	"	81	IN	2.7 V	2.7 V	2.7 V		OUT									- Q1	"		ı "
			82							"	OUT		2.7 V	2.7 V	2.7 V	IN			"		
											5					11.4		- Q2			L
		"	83							=		OUT	2.7 V	2.7 V	2.7 V	IN	"	Q2	"		"
	t <sub>PLH1</sub>	3003	84							=		OUT	IN	GND	2.7 V	IN		PR2 to Q2	5	21	ns
		Fig. 11	85	IN	2.7 V	GND	IN	OUT		-							"	PR1 to Q1	"	21	"
	t <sub>PHL1</sub>	"	86	IN	2.7 V	GND	IN		OUT	"							"	PR1 to Q1	"	28	"
		m .	87							"	OUT		IN	GND	2.7 V	IN	"	PR2 to Q2	"	"	"
	t <sub>PLH2</sub>	3003	88							"		OUT	2.7 V	2.7 V	2.7 V	IN	"	CLK2 to Q2	"	22	"
	*PLH2	Fig. 12	89								OUT	001	2.7 V	2.7 V	2.7 V	IN		_	"	"	"
		1 ig. 12									001		<i>,</i> ,	2.7 V	2 V			CLK2 to Q2			<u> </u>
		"	90	IN	2.7 V	2.7 V	2.7 V		OUT	"							"	CLK1 to Q1	"	"	"
		"	91	"	-	=	"	OUT		=							"	CLK1 to Q1	"	"	"
	t <sub>PHL2</sub>	"	92	"		=	"	OUT		=							"	CLK1 to Q1	"	30	"
		"	93	"	"	"	"		OUT	"							=	CLK1 to Q1	"	"	"
		"	94							"	OUT		2.7 V	2.7 V	2.7 V	IN	"	CLK2 to Q2	"	"	"
			95							"		OUT	2.7 V	2.7 V	2.7 V	IN		CLK2 to Q2	"	"	"
	f <sub>MAX</sub>	Fig. 11	96-99									001		, v	2., ,			OLIVE TO GE	25		MHz
	10/	1 19. 11	00 00																		1
	t <sub>PLH1</sub>	3003	100-101																5	32	ns
	*FLIII	Fig. 11																		~-	i
	t <sub>PHL1</sub>	3003	102-103	Same tes	ts and ten	minal con	ditions an	nd limits a	s for suba	roup 9 ex	cent T <sub>c</sub> =	+125°C							"	40	"
	FILL	Fig. 11		Carrio tos			a.a.o.io, ai					. 120 0.								.	i
	t <sub>PLH2</sub>	3003	104-107	1															"	32	"
	*PLM2	Fig. 12	.007																	02	i
	t <sub>PHL2</sub>	3003	108-111	1															"	42	-
	VPHL2	Fig. 12	.00																	72	i
11	Same too	ts, terminal o	conditions s	and limite a	s for subo	aroun 10	evcent T.	55°C											1		
	Currio too	io, ioiiiiiiai c	, , ,		o ioi oube	ji o up 10, i	ovoobt 16	_ 00 0.													



# 45

# MIL-M-38510/301F

TABLE III. <u>Group A inspection for device type 04</u> - Continued. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

# $\underline{4}/\ I_{IL}$ limits in mA are as follows:

			Min/Max li	mits for CRT		
Symbol	Α	В	С	D	F	E
I <sub>IL1</sub>	075/250	03/300	110/250	120/360	010/360	120/360
I <sub>IL2</sub>	175/550	060/600	150/560	240/720	240/720	280/760
I <sub>IL3</sub>	200/800	060/700	290/650	120/720	120/720	320/800

- 5/ Momentary GND, then open.
- 6/ Ios limits in mA are as follows:

Test no.	А	В	С	D and E	F
46, 48	-7.5/-50	-7.5/-50	-30/-130	-15/-130	-7.5/-50
46, 48	2.25 V	2.25 V			2.25 V
Q1, Q2					

- 7/ Input voltages shown are A = 2.0 volts minimum and B = 0.7 volts maximum.
- 8/ Tests shall be performed in sequence, attributes data only.
- $\underline{9}$ / Output voltages shall be H  $\geq$  1.5 V and L < 1.5 V.
- 10/ f<sub>MAX</sub> minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.

TABLE III. Group A inspection for device type 05. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

					1 61	IIIIIIai CO	Hullions	(piris rio	i designa	aleu may	be nign	≥ 2.0 V,	10W ≥ 0.	7 V, OI O	pen).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
Subgroup	Symbol	883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Lim	nits	Unit
			Test no.	CLR	K1	J1	PR1	Q1	- Q1	GND	_ Q2	Q2	PR2	J2	K2	CLK	V <sub>CC</sub>		Min	Max	
1	V <sub>OH</sub>	3006	1	2.0 V	0.7 V	2.0 V	0.7 V	4 mA		GND						2.0 V	4.5 V	Q1	2.5		V
Tc = 25°C		"	2	0.7 V	"	"	2.0 V		4 mA	"						2.0 V	"	_ Q1	"		"
		"	3	2.0 V	"		"	4 mA								<u>2</u> /	"	Q1	"		"
		"	4		2.0 V	0.7 V	"		4 mA	-						"	"	_ Q1	"		"
		"	5							=	4 mA		2.0 V	0.7 V	2.0 V	=	"	_ Q2	"		=
		"	6	-						-		4 mA	=	2.0 V	0.7 V	"	-	Q2	"		=
		"	7	0.7 V						=	4 mA		=	"	•	2.0 V	"	_ Q2	"		=
		"	8	2.0 V						-		4 mA	0.7 V	-	-	"	=	Q2	"		=
	V <sub>OL</sub>	3007	9	2.0 V						-	4 mA		0.7 V	"	"	"	"	_ Q2		0.4	"
		"	10	0.7 V						-		4 mA	2.0 V	-	"	"	"	Q2		"	=
		"	11	2.0 V							4 mA		"	"	"	<u>2</u> /	"	- Q2			"
		"	12	-						-		4 mA	=	0.7 V	2.0 V	-	=	Q2		-	=
		"	13	"	0.7 V	2.0 V	2.0 V		4 mA	"						"	"	_ Q1			"
		"	14	"	2.0 V	0.7 V	2.0 V	4 mA		"						"	"	Q1		"	"
		"	15	"		"	0.7 V		4 mA	"						2.0 V	"	_ Q1			"
		"	16	0.7 V		-	2.0 V	4 mA		"						2.0 V	-	Q1		-	"
	V <sub>IC</sub>		17	-18 mA						-							"	CLR		-1.5	=
			18		-18 mA					-							-	K1			=
			19			-18 mA				-							"	J1		"	=
			20				-18 mA			-							"	PR1		"	-
			21							-			-18 mA				"	PR2		"	-
			22							"				-18 mA			"	J2			=
			23							-					-18 mA		"	K2			"
			24							-						-18 mA	"	CLK		"	".
	I <sub>IL1</sub>	3009	25	4.5 V	0.4 V	GND	<u>3</u> /			- "						4.5 V	5.5 V	K1	<u>4/</u>	4/	mA "
		"	26	<u>3</u> /	GND	0.4 V	4.5 V			- "			4.5.1	0.41/	4.5.1/	<u> </u>		J1	- "		- "
		"	27	<u>3</u> /						- "			4.5 V	0.4 V	4.5 V	<u> </u>		J2	- "		- "
		"	28	4.5 V						- "			3/	4.5 V	0.4 V	- "	-	K2	- "	-	-
	I <sub>IL4</sub>		29 30		4.5 V	4.5 V	0.4 \/						0.4 V	4.5 V	4.5 V	-	-	PR2 PR1		-	-
		"	30	3/	4.5 V	4.5 V	0.4 V 4.5 V						4.5 V	4.5 V	4.5 V	0.4 V		CLK	-		
	I <sub>IL6</sub>		32	<u>3</u> / 4.5 V			4.5 V						4.5 V	4.5 V	4.5 V 4.5 V	0.4 V		CLK			
	lo =		33	0.4 V	4.5 V	4.5 V	4.5 V						4.5 V	4.5 V	4.5 V	4.5 V	"	CLR			
	I <sub>IL7</sub>	3010	34	GND	2.7 V	GND	GND						4.5 V	4.5 V	4.5 V	GND		K1		20	μА
	IIH1	3010	35	UND "	GND	2.7 V	GND			"						"	"	J1		20	μA "
			36	"	GIVD	Z.1 V	GIVD						GND	2.7 V	GND			J2		"	"
			37	"									UIVD "	GND	2.7 V	"	"	K2		"	"
		ļ	- 5,									ļ		0.40	Z.1 V	<u> </u>	L	114			

See footnotes at end of device type 05.

TABLE III. Group A inspection for device type 05 - Continued. Terminal conditions (pins not designated may be high  $\geq 2.0 \text{ V}$ , low  $\leq 0.7 \text{ V}$ , or open).

					Te	rminal co	nditions	(pins no	t designa	ated may	<sup>,</sup> be high	≥ 2.0 V,	low $\leq 0$ .	7 V, or o	pen).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
Subgroup	Symbol	883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Lim	nits	Unit
			Test no.	CLR	K1	J1	PR1	Q1	_ Q1	GND	_ Q2	Q2	PR2	J2	K2	CLK	V <sub>cc</sub>		Min	Max	
1	I <sub>IH2</sub>	3010	38	GND						GND			GND	GND	5.5 V	GND	5.5 V	K2		100	μΑ
Tc = 25°C		"	39	"						"			GND	5.5 V	GND	"	"	J2		"	<u>"</u>
		"	40	"	GND	5.5 V	GND			"						"	"	J1		"	"
			41	"	5.5 V	GND	GND			"						"	"	K1		"	"
	I <sub>IH5</sub>		42	"	GND	GND	2.7 V			"						"	"	PR1		60	"
		=	43	"						"			2.7 V	GND	GND	"	"	PR2		60	"
	I <sub>IH6</sub>	-	44	"						"			5.5 V	GND	GND	"	"	PR2		300	"
		=	45	"	GND	GND	5.5 V			"						"	"	PR1		300	"
	I <sub>IH9</sub>		46	2.7 V	"	"	GND			"			GND	GND	GND	"	"	CLR	<u> </u>	120	"
	I <sub>IH10</sub>	-	47	5.5 V	"	"	"			"			"	"	"	"	"	CLR		600	"
	I <sub>IH11</sub>	"	48	GND	"	"	"			"			"	"	"	2.7 V	"	CLK		160	"
	I <sub>IH12</sub>	-	49	"	"	"	"			"			"	"	"	5.5 V	"	CLK		800	"
	los	3011	50	"			4.5 V		GND	"							"	_ Q1	-15	-100	mA
		"	51	"						"	GND		4.5 V				"	_ Q2	"	"	"
			52	4.5 V						"		GND	GND				"	Q2	"	"	"
			53	4.5 V			GND	GND		"								Q1	"	"	"
	I <sub>cc</sub>	3005	54	GND	5.5 V	5.5 V	5.5 V			"			5.5 V	5.5 V	5.5 V	GND	"	V <sub>cc</sub>		8.0	"
	00		55	5.5 V	5.5 V	5.5 V	GND			"			GND	5.5 V	5.5 V	GND	"	V <sub>CC</sub>		8.0	"
2	Same tes	sts, terminal	conditions, a	and limits a	as for sub	group 1, e	xcept T <sub>C</sub> =	= +125°C	and V <sub>IC</sub> te	sts are or	nitted.										
3		sts, terminal																			
7 <u>5</u> /, <u>6</u> /	Truth	3014	56	В	В	Α	Α	L	Н	GND	Н	L	Α	Α	В	Α	4.5 V	All		See <u>7</u> /	
Tc = 25°C	table	"	57	"	"	"	"	-	-	"	"	"	"	"	=	В	"	outputs			
	tests		58	"	"	"	"	"	"	"	"	"	"	"	"	Α	"	"		"	
		"	59	Α	"	"	"	-	-	"	L	Н	В	В	=	Α	"	"			
		"	60	"	"	"	"	Н	L	"	"	"	"	"	"	В	"	"		"	
		"	61	-	"	-	"	-	-	"	"		-		-	Α	"	"		"	
			62	"	"	В	"	"	"	"	"	"	"	"	"	Α	"	"		"	
			63	"	"	"	"	"	"	"	"	"	"	"	"	В	"	"		"	
			64	"	"	"	"	"	"	"	"	"	"	"	"	Α	"	"		"	
		"	65	"	Α	"	"	"	=	"	"	"	"	"	"	Α	"	"		"	
		"	66	"	"	"	"	L	Н	"	"	"	"	"	"	В	"	"	<u> </u>	"	
			67	"	"	"	"	L	Н	"	"	"	"	"	"	Α	"	"	<u> </u>	"	
			68	"		"	В	Н	L	"	"			"	"	A			<b></b>		
			69				В	Н	L	"	"		- "-			В			<b></b>		
			70	В	В	"	A	L	H	"	Н	L	A	A	"	A	- "	- "	<b></b>	"	
			71	A			В	Н	L		Н	L				A			<b></b>		
			72	"	"	"	"		"	"	L "	H		- "		В	"		<del> </del>	-	
			73			- "	- "		- "	"	"		<del></del>			A	<u> </u>		<b> </b>		
			74 75		"			-		"	"	- "	- "	B "		A B	-		ļ	-	

See footnotes at end of device type 05.

TABLE III. Group A inspection for device type 05 - Continued.

Tarminal conditions (n	a not decimated may	, he high > 2 0 1/ love < 0 7 1/ or onen)
reminal conditions (p	is not designated may	be high $\geq 2.0 \text{ V}$ , low $\leq 0.7 \text{ V}$ , or open).

							mullions							7 V, or o							
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
Subgroup	Symbol	883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Lin	nits	Unit
		metriod	Test no.	CLR	K1	J1	PR1	Q1	_ Q1	GND		Q2	PR2	J2	K2	CLK	V <sub>CC</sub>	terminai	Min	Max	
7 <u>5</u> /, <u>6</u> /	Truth	3014	76	Α	В	В	В	Н	L	GND	L	Н	Α	В	В	Α	4.5 V	All		See 7/	
Tc = 25°C	table	3014	77	"	"	"	"	"	"	UND	"	"	"	"	A	A	4.5 V	outputs		"	
10 = 23 0	tests	"	78	,	"						Н					В		outputs "			
	lesis	"	79	,							H	L			,,	A		"			
			80	,		,			,		I	Н	В			A				-	
		"	81	,		"					L		 "		,,	В		"			
		"	82	В	Α	Α			Н		Н			Α	,,	A		"			
		"	83	В	В	В	Α	L	"		"		Α	В	В			"			
		"	84	A	"	"		-	"		"	-		"	"		"	"			
		"	85	A			"	"	"		"	"				В	"	"			
		"	86	"	Α	Α	"	"		"	"	"		Α	Α	В	"	"		-	
		"	87	"	"	"	"	"		"	"	"		"	"	A	"	"		-	
		"	88	"	"	"	"	Н	1	"	L	Н			"	В	"	"		-	
		"	89	"	В	В	"	"	"	"	"	"		В	В	В	"	"		-	
			90	"	"	"	"	"	"	"	"	"		-	"	A	"	"		"	
		"	91	"	"	"	"	"	"	"	"	"			"	В	"	"			
			92	"	Α	Α	"	"	"		"	"	"	Α	Α	В	"	"		"	
		"	93	"	"	"	"	"		"	"	"		"	"	A	"	"		-	
		"	94	"	"	"	"	-	Н	"	Н	1			"	В	"	"		-	
8 <u>4</u> /, <u>5</u> /	Paneat s	ubgroup 7 at		and T <sub>-</sub> -	-55°C	l	l			l							l				
9	f <sub>MAX</sub>	Fig. 9	95	5.0 V	2.7 V	2.7 V	2.7 V	OUT		GND		1				IN	5.0 V	Q1	25		MHz
Tc = 25°C	7/	1 ig. 9	96	3.0 V	2.7 V	2.7 V	2.7 V	001	OUT	"						"	3.0 V	Q1 Q1	"		"
		"	97	"						"	OUT		2.7 V	2.7 V	2.7 V	"	"	Q2	"		"
		"	98	"						"		OUT	2.7 V	2.7 V	2.7 V	"	ı	Q2	"		"
	t <sub>PLH1</sub>	3003	99	IN	GND	2.7 V	2.7 V		OUT	"						"	"	CLR to Q1	5	21	ns
		Fig. 9	100	IN						"	OUT		2.7 V	2.7 V	GND	"	"	CLR to Q2	"	"	"
		"	101	2.7 V						"		OUT	IN	GND	2.7 V	"	"	PR2 to Q2	"	"	"
		"	102	"	2.7 V	GND	IN	OUT		"						"	"	PR1 to Q1	"	"	"
	t <sub>PHL1</sub>	"	103	"	2.7 V	GND	IN		OUT	"						"	"	PR1 to Q1	"	28	"
		H	104	"						"	OUT		IN	GND	2.7 V	"	"	PR2 to Q2	"	"	"
		"	105	IN						"		OUT	2.7 V	2.7 V	GND	"	"	CLR to Q2	"	"	"
		"	106	IN	GND	2.7 V	2.7 V	OUT		"						"	"	CLR to Q1	"	"	"
	t <sub>PLH2</sub>	3003	107	2.7 V	2.7 V	2.7 V	2.7 V	OUT		"						"	"	CLK to Q1	"	22	"
	-1 212	Fig. 10	108	"	2.7 V	2.7 V	2.7 V		OUT	"						"	"	CLK to Q1	"	"	"
		"	109	"						"	OUT		2.7 V	2.7 V	2.7 V	"	"	CLK to Q2	"	"	"
		"	110	"					1	"		OUT	2.7 V	2.7 V	2.7 V	"	"	CLK to Q2		"	"
	tou :: a	"	111	"					<del> </del>	"		OUT	2.7 V	2.7 V	2.7 V	"		CLK to Q2	"	30	-
	t <sub>PHL2</sub>	"	112	"						"	OUT	001	2.7 V	2.7 V	2.7 V	"	"	CLK to Q2	"	"	"
		"	113	"	2.7 V	2.7 V	2.7 V		OUT	"						"	"	CLK to Q1	"	"	"
		"	114	"	2.7 V	2.7 V	2.7 V	OUT	<del> </del>	"			-	-		"	"	CLK to Q1	"	"	"
									1	1	1		1	1			1			1	

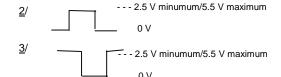
See footnotes at end of device type 05.

# TABLE III. Group A inspection for device type 05 - Continued.

Terminal conditions (pins not designated may be high > 2.0 V. low < 0.7 V. or open).

					101	minar oc	Haltiono	(Pirio rio	t accignic	itou may	De High	,	1011 _ 0.	, v, o. o	0011).						
			Cases 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
		MIL-STD-	2, X																		
Subgroup	Symbol	883	Cases	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured	Lin	nits	Unit
	, i	method	A,B,C,D															terminal			
			Test no.	CLR	K1	J1	PR1	Q1	_ Q1	GND	_ Q2	Q2	PR2	J2	K2	CLK	V <sub>cc</sub>		Min	Max	
10	f <sub>MAX</sub>	Fig. 9	115-118						ı					ı	ı				25		MHz
	<u>8</u> /																				
	t <sub>PLH1</sub>	3003	119-122																5	32	ns
		Fig. 9		Same tes	ts and ter	minal con-	ditions as	for subgro	oup 9, exc	ept T <sub>C</sub> = +	⊦125°C.										
	t <sub>PHL1</sub>	3003	123-126																"	40	
		Fig. 9																			
	t <sub>PLH2</sub>	3003	127-130																"	32	-
		Fig. 10																			
	t <sub>PHL2</sub>	3003	131-134																"	42	
		Fig. 10																			
11	Same tes	sts, terminal o	conditions, a	and limits a	as for subg	group 10,	except T <sub>C</sub>	= -55°C.													

1/ Case X and 2 pins not referenced are NC.



4/ I<sub>IL</sub> limits in mA are as follows:

•	<u> </u>	113 1 410 40 1011	01101			
				Min/Max limits	for CKT	
	I <sub>IL1</sub>	Α	В	С	D	E
		075/250	030/300	110/250	120/360	120/360

			Min/Max limits	for CKT	
$I_{IL4}$	Α	В	С	D	ш
	200/800	060/700	290/650	120/720	320/800

Г				Min/Max limits	for CKT	
	I <sub>IL6</sub>	Α	В	С	D	Е
		300/-1.000	120/-1.000	300/-1.120	240/-1.440	560/-1.520

			Min/Max limits	for CKT	
I <sub>IL7</sub>	Α	В	С	D	Е
	450/-1.300	120/-1.000	580/-1.300	120/-1.500	640/-1.600

- $\underline{5}/$  Input voltages shown are A = 2.0 volts minimum and B = 0.7 volt maximum.  $\underline{6}/$  Tests shall be performed in sequence, attributes data only.

- 7/ Output voltages shall be H  $\geq$  1.5 V and L < 1.5 V. 8/  $f_{MAX}$  minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.

TABLE III. <u>Group A inspection for device type 03 and 10</u>. Terminal conditions (pins not designated may be high  $\ge 2.0 \text{ V}$ , low  $\le 0.7 \text{ V}$ , or open). 1/2

													high ≥ 2										
			Cases 1/	* 2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				ľ
		MIL-STD-	2, X	** 2	20	5	3	19	18	13	17	14	9	12	15	8	10	4	7				1
Subgroup	Symbol	883	Cases	* 1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured	Lim	nits	Unit
		method	E, F	** 1	16	4	2	15	14	10	13	11	7	9	12	6	8	3	5	terminal			1
			Test no.	CLK1	K1	J1	PR1	Q1		Q2	GND	Q2	PR2	J2	K2	CLK2	CLR2	CLR1	V <sub>CC</sub>		Min	Max	1
			10011101					Ψ.	Q1	Q2		Ψ.		02		02.42	OLITE					max	
1	V <sub>OH</sub>	3006	1	2.0 V	2.0 V	2.0 V	2.0 V		4 mA		GND							0.7 V	4.5 V	_ Q1	2.5		V
Tc = 25°C		"	2	2.0 V	"	2.0 V	0.7 V	4 mA			"							2.0 V	"	Q1	"		"
		"	3	<u>3</u> /	"	0.7 V	2.0 V		4 mA		"									_ Q1	"		
			4	3/	0.7 V	2.0 V	2.0 V	4 mA										"	"	Q1			"
		"	5	<u> </u>	0 1	2.0 1	2.0 .				"	4 mA	0.7 V	2.0 V	2.0 V	2.0 V	2.0 V		"	Q2	"		"
			6							4 mA	"		2.0 V	"	2.0 V	2.0 V	0.7 V			 Q2	"		
		_																					<b>—</b> —
			7								- "	4 mA	"	"	0.7 V	<u>3</u> /	2.0 V		"	Q2			— <u>"</u>
			8							4 mA	"		"	0.7 V	2.0 V					_ Q2			1
	V <sub>OL</sub>	3007	9								"	4 mA		0.7 V	2.0 V	"	"		"	Q2		0.4	"
	. 02	"	10							4 mA	"			2.0 V	0.7 V	"	"		"	Q2		"	"
														0.01/	0.01/	0.01/	0.71/						<del></del>
			11 12							4 m Λ	- "	4 mA	0.7 V	2.0 V 2.0 V	2.0 V 2.0 V	2.0 V	0.7 V			Q2			
			12							4 mA			0.7 V	2.0 V	2.0 V	2.0 V	2.0 V			_ Q2			1
		"	13	2.0 V	2.0 V	2.0 V	2.0 V	4 mA			"							0.7 V	"	Q1		"	"
		"	14	2.0 V	"	2.0 V	0.7 V		4 mA		"							2.0 V		_ Q1		"	
			15	3/	"	0.7 V	2.0 V	4 mA										"	"	Q1		"	"
		"	16	<u>3</u> /	0.7 V	2.0 V	2.0 V		4 mA		"							"	"	Q1		"	"
	V <sub>IC</sub>		17	-18 mA																CLK1		-1.5	-
	• 10		18	1011111	-18 mA						"									K1		"	"
			19			-18 mA					"								"	J1		"	"
			20				-18 mA													PR1		"	"
			21								"		-18 mA						-	PR2		-	-
			22								"			-18 mA						J2		"	
			23								"				-18 mA					K2			- :
			24								- "					-18 mA				CLK2			<del></del>
			25														-18 mA	-18 mA		CLR2 CLR1			
	l	3009	26 27	4.5 V	0.4 V	4.5 V	4/				"					-		4.5 V	5.5 V	K1	5/	5/	mA
	I <sub>IL1</sub>	3009	28	4.5 V	4.5 V	0.4 V	4.5 V				"							4.5 V	J.J V	J1	<u>J</u> /	<u>J</u> /	"
		"	29	7.5 V	7.0 V	0∓ V	7.5 V				"		4.5 V	0.4 V	4.5 V	4.5 V	4/	-11		J2	"	"	"
		"	30								"		4/	4.5 V	0.4 V	4.5 V	4.5 V		"	K2	"	"	"
	I <sub>IL3</sub>	"	31								"		4/	4.5 V	4.5 V	0.4 V	4.5 V		"	CLK2	"	"	"
		"	32								"		4.5 V	4.5 V	4.5 V	0.4 V	<u>4</u> /		"	CLK2	"	"	"
		"	33	0.4 V	4.5 V	4.5 V	4.5 V				"							<u>4</u> /		CLK1	"		"
		"	34	0.4 V	4.5 V	4.5 V	<u>4</u> /				"							4.5 V	"	CLK1	"	"	
	$I_{IL4}$		35	4.5 V	4.5 V	4.5 V	0.4 V				- "							4.5 V	"	PR1	- "	"	<del>- "-</del>
			36	4.5 V	4.5 V	4.5 V	4.5 V				- "		4 5 \/	451/	451/	451/	0.41/	0.4 V		CLR1		- "	
		,	37 38	-							"		4.5 V 0.4 V	4.5 V	4.5 V	4.5 V 4.5 V	0.4 V		"	CLR2			
	l	3010	38		-						"		GND	4.5 V 4.5 V	4.5 V 2.7 V	GND	4.5 V 4.5 V		"	PR2 K2		20	μА
	I <sub>IH1</sub>	3010	40								"		4.5 V	2.7 V	4.5 V	GND	GND		"	J2		20	μA "
		"	41	GND	4.5 V	2.7 V	4.5 V						4.J V	Z.1 V	4.5 V	GND	GIND	GND	"	J1		"	"
		"	42	GND	2.7 V	4.5 V	GND							1		1		4.5 V	"	K1		"	"
				, 5,10	, *		<u> </u>	<b></b>								ь	·				·		

See footnotes at end of device types 03 and 10.

TABLE III. <u>Group A inspection for device type 03 and 10</u>. Terminal conditions (pins not designated may be high  $\ge 2.0 \text{ V}$ , low  $\le 0.7 \text{ V}$ , or open). 1/2 I

						ren	ninai co	mailions	s (pins r	ioi desi	gnated r	nay be	high ≥ 2	.0  V, 10V	V ≤ U.7 V	, or ope							
			Cases 1/	* 2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
		MIL-STD-	2, X	** 2	20	5	3	19	18	13	17	14	9	12	15	8	10	4	7				ĺ
Subgroup	Symbo	883	Cases	* 1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured	Lim	nits	Unit
	•	method	E, F	** 1	16	4	2	15	14	10	13	11	7	9	12	6	8	3	5	terminal			l
			Test no.	CLK1	K1	J1	PR1	Q1	_ Q1	_ Q2	GND	Q2	PR2	J2	K2	CLK2	CLR2	CLR1	V <sub>cc</sub>	1	Min	Max	1
1	I <sub>IH2</sub>	3010	43	GND	5.5 V	4.5 V	GND				GND							4.5 V	5.5 V	K1		100	μА
Tc = 25°C		"	44	GND	4.5 V	5.5 V	4.5 V				"							GND	"	J1		"	"
		"	45								"		4.5 V	5.5 V	4.5 V	GND	GND		"	J2		"	"
		"	46								"		GND	4.5 V	5.5 V		4.5 V		"	K2		"	"
	I <sub>IH5</sub>	"	47								"		<u>4</u> /	GND	4.5 V		2.7 V		"	CLR2		60	"
		"	48								"		2.7 V	4.5 V	GND		<u>4</u> /		"	PR2		"	"
		"	49	GND	4.5 V	GND	4/				"							2.7 V	"	CLR1		"	"
		"	50	GND	GND	4.5 V	2.7 V											<u>4</u> /	"	PR1		"	"
	I <sub>IH6</sub>	"	51	GND	GND	4.5 V	5.5 V											<u>4</u> /	-	PR1		300	
		"	52	GND	4.5 V	GND	<u>4</u> /				"							5.5 V	"	CLR1		-	
		"	53								"		5.5 V	4.5 V	GND	GND	<u>4</u> /		-	PR2		-	
		"	54								"		4/	GND	4.5 V	GND	5.5 V			CLR2			-
	$I_{IH7}$	"	55								"		GND	GND	GND	2.7 V	GND		"	CLK2		80	
		"	56	2.7 V	GND	GND	GND				"							GND	"	CLK1		80	"
	I <sub>IH8</sub>	"	57	5.5 V	GND	GND	GND				"							GND	"	CLK1		400	"
		"	58								"		GND	GND	GND	5.5 V	GND		"	CLK2		400	"
	los	3011	59	GND	GND	GND	GND	GND			"							4.5 V	"	Q1	-15	-100	mA
		"	60	GND	GND	GND	4.5 V		GND		"							GND	"	_ Q1	"	"	. "
		"	61	-	-						-	GND	GND	GND	GND	GND	4.5 V		-	Q2			-
		"	62							GND	"	GIND	4.5 V	"	"	"	GND			- Q2 - Q2			
	1	3005	63	GND	GND	GND	GND						GND	"			5.5 V	5.5 V	,	V <sub>CC</sub>		8.0	
	Icc	3005	64	GND	GND	GND	5.5 V				"		5.5 V	,			GND	GND		V <sub>CC</sub>		8.0	
2	Come to	ests, termina						.42500	and \/ . to	*** *** ***	ittaal	l .	3.5 V				GND	GND	ı	V <sub>CC</sub>		0.0	
		ests, termina																					
7 <u>6</u> /, <u>7</u> /	Truth	3014	65	B B	B as for sur	A A	A A	= -55°C ar	H H	H H	GND		Α	А	В	В	В	В	4.5 V	All		See 8/	
Tc = 25°C	table	3014	66	A	B "	A	A				UND "		A	A		A	_ D	В	4.5 V	outputs		3ee <u>o</u> /	
10 = 25 0	tests		67	В												B				outputs "		-	
	เยรเร	"	68	В	Α	В	В	Н				Н	В	В	Α	В	Α	Α		"		-	
		"	69	A		"	"	- 11	-	-		- 11	"	"	-	A				"		-	
		"	70	В		"	"		"					"		В				"		-	
		"	71	"	В		Α		Н	Н	-		Α		В	ı ı	В	В		"		-	
		"	72		ı ı			-	"	"	-	-			"		A	A		"		-	
		"	73	Α	-	"	"	"	"	"	-			"		Α	-		-	"			
		"	74	В	-	"	"	"	"	"	-			"		В			-	"			
		"	75	"	"	"	В	Н				Н	В	"		"	"			"			
		"	76		"	"	A	- ''	"	"	"	- "	A	"		"	"			"			
		"	77	Α	-	"		"	"	"	-		-	"		Α			-	"			
		"	78	В	-	"	"	"	"	"	-			"		В			-	"			
		"	79	"	"	Α	"	1	Н	Н	"	<del>                                     </del>	"	Α		"	В	В		"			
		"	80		"	"	"	-	"	"	"	-		"			A	A		"		-	
			- 00	1		L								L		L				1			

See footnotes at end of device types 03 and 10.

TABLE III. Group A inspection for device type 03 and 10.

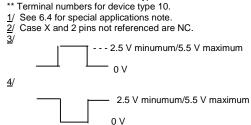
						Ter	minal co				anated i		high ≥ 2			or ope	n). 1/						
			Cases 1/	* 2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
		MIL-STD-	2, X	** 2	20	5	3	19	18	13	17	14	9	12	15	8	10	4	7				l
Subgroup	Symbol	883	Cases	* 1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured	Lim	nits	Unit
3	-,	method	E, F	** 1	16	4	2	15	14	10	13	11	7	9	12	6	8	3	5	terminal			1
			Test no.	CLK1	K1	J1	PR1	Q1	_ Q1	_ Q2	GND	Q2	PR2	J2	K2	CLK2	CLR2	CLR1	V <sub>CC</sub>	1 1	Min	Max	
7 <u>6</u> /, <u>7</u> /	Truth	3014	81	Α	В	Α	Α	L	Н	Н	GND	L	Α	Α	В	Α	Α	Α	4.5 V	All		See <u>8</u> /	
Tc = 25°C		"	82	В	"		"	Н	Ĺ	Ĺ	"	H		"		В	"		"	outputs		"	
	tests	"	83	"	Α	В	В	"	"	"	"	"	В	В	Α	"	"	=	"	"		"	
		"	84	-	"	"	Α	"	"	"	"	-	Α	"	-	"	-	-		"		"	
			85	Α	"	"	"		"	"	"	"		"		Α	"		"	"			
			86	В	-:-	"		L	H	H	- "	L.	"	"		В	-		<u> </u>	"			
			87 88	A B	"	Α "	B A	H	"	"	"	H	B A	Α "		A B	B B	B B	-	"			
			89	В	"		- A	"	"	"	"	-	A	"		В	A	A		"			
			90	A		"	"	"	"	"	"			"		A	"	"		"		-	
		"	91	В	"	"	"	Н	L	L	"	Н	"	"	"	В	"	"		"			
		"	92	Α	"	"	"	Н	L	L	"	Н	-	"	"	Α	"	"	"	"		-	
		"	93	В	"	"	"	L	Н	Н	"	L	"	"	"	В	"	"	"	"	-		
		subgroup 7				071/	0.71/	OUT	1		OND					1		0.71/	501/		0.5		
9	f <sub>MAX</sub>	Fig. 9	94	IN IN	2.7 V	2.7 V	2.7 V	OUT	OUT		GND "							2.7 V 2.7 V	5.0 V	Q1	25		MHz "
Tc = 25°C	<u>9</u> /		95	IIN	2.7 V	2.7 V	2.7 V		001									2.7 V		Q1			l
		"	96							OUT	"		2.7 V	2.7 V	2.7 V	IN	2.7 V			_ Q2			"
		"	97								"	OUT	2.7 V	2.7 V	2.7 V	IN	2.7 V		"	Q2			"
	t <sub>PLH1</sub>	3003	98 <u>10</u> /	IN	GND	2.7 V	2.7 V		OUT		"							IN	"	CLR1 to Q1	5	21	ns
		Fig. 9	99	IN	2.7 V	GND	IN	OUT			"							2.7 V	"	PR1 to Q1	"	"	"
		"	100							OUT	"		2.7 V	2.7 V	GND	IN	IN		"	CLR2 to Q2	"	"	"
		"	101								"	OUT	IN	GND	2.7 V	IN	2.7 V		"	PR2 to Q2	"	"	"
	t <sub>PHL1</sub>	"	102 <u>10</u> /								"	OUT	2.7 V	2.7 V	GND	IN	IN		"	CLR2 to Q2	"	28	"
		"	103							OUT	"		IN	GND	2.7 V	IN	2.7 V			PR2 to Q2	"	"	
		"	104	IN	GND	2.7 V	2.7 V	OUT			-							IN	"	CLR1 to Q1	"	"	
		"	105	IN	2.7 V	GND	IN		OUT									2.7 V		PR1 to Q1		"	
	t <sub>PLH2</sub>	3003	106	IN	2.7 V	2.7 V	2.7 V		OUT									2.7 V	"	CLK1 to Q1	"	22	"
		Fig. 10	107	IN	2.7 V	2.7 V	2.7 V	OUT			"							2.7 V	"	CLK1 to Q1		"	"
		ŭ,	108							OUT	"		2.7 V	2.7 V	2.7 V	IN	2.7 V		"	CLK2 to Q2	"	"	"
			109								,	OUT	271/	271/	271/	INI	271/						-
	tourr	"	110		1	1					"	OUT	2.7 V 2.7 V	2.7 V 2.7 V	2.7 V 2.7 V	IN IN	2.7 V 2.7 V		"	CLK2 to Q2 CLK2 to Q2		30	
	t <sub>PHL2</sub>	"	111							OUT	"	001	2.7 V	2.7 V	2.7 V	IN	2.7 V		"			"	"
											L									CLK2 to Q2			<del></del>
			112	IN IN	2.7 V	2.7 V	2.7 V	OUT	O' IT		- "							2.7 V	- "	CLK1 to Q1			
			113	IN	2.7 V	2.7 V	2.7 V		OUT									2.7 V		CLK1 to Q1	-		-
10	f <sub>MAX</sub>	Fig. 9	114-117		•	•		•							•					•	25		MHz
	t <sub>PLH1</sub>	3003	118-121					Sam	e tests and	terminal	conditions	as for sul	ogroup 9, e	cept T <sub>C</sub> =	+125°C					-	5	32	ns
	t <sub>PHL1</sub>	Fig. 9 3003	122-125																			40	"
	t <sub>PLH2</sub>	Fig. 9 3003	126-129																	}		32	"
		Fig. 10																		]			
	t <sub>PHL2</sub>	3003 Fig. 10	130-133																		"	42	"
11	Same to		ninal conditi	ons as for	subgroup	10, excep	t T <sub>C</sub> = -55°	С												•			

See footnotes at end of device types 03 and 10.

# TABLE III. Group A inspection for device type 03 and 10.

Terminal conditions (pins not designated may be high  $\geq 2.0 \text{ V}$ , low  $\leq 0.7 \text{ V}$ , or open).  $1/\sqrt{100}$ 

- \* Terminal numbers for device type 03.
- \*\* Terminal numbers for device type 10.



5/ I<sub>IL</sub> limits in mA are as follows:

			Mir	n/Max limits for C	CKT	
I	.1	Α	В	С	D	E
		075/250	030/300	150/560	120/360	120/360

		Min	/Max limits for C	CKT	
I <sub>IL3</sub>	Α	В	С	D	E
	150/500	060/600	250/560	240/720	280/760

		Min	/Max limits for C	KT	
$I_{IL4}$	Α	В	С	D	E
	200/800	060/700	290/650	120/720	320/800

- $\underline{6}$ / Input voltages shown are A = 2.0 volts minimum and B = 0.7 volts maximum.
- 7/ Tests shall be performed in sequence, attributes data only.
- $\underline{8}/$  Output voltages shall be H  $\geq$  1.5 V and L < 1.5 V.
- g/ f<sub>MAX</sub> minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.
- $\underline{10}$ / These tests may be performed as shown in table III or alternately as follows:

Test no.	CLK1	K1	J1	PR1	Q1	_ Q1	Q2	GND	Q2	PR2	J2	K2	CLK2	CLR2	CLR1	V <sub>CC</sub>
98A	2.7 V	2.7 V	2.7 V	<u>2</u> /		OUT		GND							IN	5.0 V
99A	2.7 V	2.7 V	2.7 V	IN	OUT			"							2/	"
100A							OUT	"		<u>2</u> /	2.7 V	2.7 V	2.7 V	IN		"
101A								"	OUT	IN	2.7 V	2.7 V	2.7 V	<u>2</u> /		"
102A								"	OUT	<u>2</u> /	2.7 V	2.7 V	2.7 V	IN		=
103A							OUT	"		IN	2.7 V	2.7 V	2.7 V	<u>2</u> /		=
104A	2.7 V	2.7 V	2.7 V	<u>2</u> /	OUT			"							IN	"
105A	2.7 V	2.7 V	2.7 V	IN		OUT		"							<u>2</u> /	"

TABLE III. <u>Group A inspection for device type 06</u>. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

						16	erminai	conaitio	ns (pins	not des	signated	i may b	e high ≥	2.0 V, K	$5W \le 0.7$	v, or op	en).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
Subgroup	Symbol	883 method	Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Lim	iits	Unit
			Test no.	CLR	Q1	D1	D2	Q2	D3	Q3	GND	CLK	Q4	D4	Q5	D5	D6	Q6	V <sub>CC</sub>		Min	Max	l
1	V <sub>OH</sub>	3006	1	2.0 V	4 mA	2.0 V					GND	2/							4.5 V	Q1	2.5		V
Tc = 25°C	0	"	2	"			2.0 V	4 mA												Q2			
		"	3	"					2.0 V	4 mA										Q3			
		"	4	"							"		4 mA	2.0 V					"	Q4	"		"
		"	5	"							"	"			4 mA	2.0 V				Q5	"		"
		"	6	"							"						2.0 V	4 mA	"	Q6			"
	V <sub>OL</sub>	3007	7	"													0.7V	4 mA		Q6		0.4	"
		"	8	"											4 mA	0.7 V			"	Q5			"
		"	9	"							"		4 mA	0.7 V					"	Q4			
		"	10	"					0.7 V	4 mA									"	Q3		"	"
		"	11	"			0.7 V	4 mA											"	Q2		"	"
		"	12	"	4 mA	0.7 V													"	Q1		"	"
		"	13	0.7 V	4 mA						"								"	Q1		"	"
		"	14	=				4 mA			=									Q2		=	"
		"	15	=						4 mA	=								"	Q3		=	
		"	16	"									4 mA							Q4		-	
		"	17	"							"				4 mA				"	Q5		"	-
		"	18	"							"							4 mA	"	Q6		"	-
	V <sub>IC</sub>		19	-18 mA															"	CLR		-1.5	
			20			-18 mA					"								"	D1			
			21				-18 mA				=								"	D2			
			22						-18 mA										"	D3			
			23								"	-18 mA							_ "	CLK		"	
			24								"			-18 mA					"	D4		"	
			25								"					-18 mA			"	D5			"
			26								- "						-18 mA			D6			<u> </u>
	I <sub>IL1</sub>	3009	27								"					0.417	0.4 V		5.5 V	D6	<u>3</u> /	<u>3</u> /	mA "
			28								- "			0.41/		0.4 V				D5		- "	<del>-</del>
			29						0.41/		-			0.4 V					"	D4		- "	<del>-</del>
			30 31				0.4 V		0.4 V										-	D3 D2		- "	<del>-</del>
		"	32			0.4 V	0.4 V				-								-	D2		"	
			33	0.4 V		0.4 V													"	CLR		"	-
	I <sub>IL2</sub>	"	34	0.4 V								0.4 V								CLK	-		-
	I <sub>IH1</sub>	3010	35	2.7 V		<u> </u>					"	0.4 V		<b> </b>						CLR		20	μА
	'IH1	"	36	Z.1 V		2.7 V								<b>†</b>					"	D1		"	μΛ
		"	37			Z.1 V	2.7 V							<b>†</b>					"	D2			-
		"	38				Z.1 V		2.7 V					<b>†</b>					"	D3			-
		"	39						Z.1 V		"	2.7 V		<b>†</b>					"	CLK			-
		"	40			t	1	1			"	2.7 V		2.7 V		t			"	D4			
		"	41			t	1	1			"			∠.1 V		2.7 V			"	D5			
		"	42			1					"					2.7 V	2.7 V		"	D6		"	
	I <sub>IH2</sub>	"	43								"			<b> </b>			5.5 V			D6		100	"
	·IIIZ	"	44								"			<b> </b>		5.5 V	0.0 .		"	D5		"	"
		"	45								"			5.5 V		0.0 7			"	D4			"
		"	46								"	5.5 V							"	CLK			"
		"	47						5.5 V					Ì					"	D3			"
		"	48				5.5 V							Ì					"	D2			
		"	49			5.5 V					"			Ì					"	D1		"	"
		"	50	5.5 V		1										1			"	CLR			

See footnotes at end of device types 06.

TABLE III. Group A inspection for device type 06 - Continued.

						Te	erminal o	conditio	ns (pins	not des	signated	l may b	e high ≥	2.0 V, Ic	$w \le 0.7$	V, or op	en).						
			Cases 1/	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
		MIL-STD-	2, X																				ı
Subgroup	Symbol	883	Cases	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured	Lim	its	Unit
Oubgroup	Cymbol	method	E, F		_			U				Ŭ	10			10				terminal		iito	ı
				CLR	Q1	D1	D2	Q2	D3	Q3	GND	CLK	Q4	D4	Q5	D5	D6	Q6	\/		Min	Max	
1		3011	Test no. 51	4.5 V	GND	4.5 V	DZ	Q2	D3	Q3	GND	4/	Q4	D4	ŲЭ	טט	D6	Qb	V <sub>CC</sub> 5.5 V	Q1	-15	-100	^
l l	los	3011	52	4.5 V	GIND	4.5 V	4.5 V	GND			GIND "	4/							3.3 V	Q2	-13	-100	μA "
Tc = 25°C			53	-			4.5 V	GIND	4.5 V	GND	-								-	Q2 Q3		-	
			53	"	-				4.5 V	GND	-	-	GND	4.5 V					"	Q3 Q4	-	-	
			55	"							"		GND	4.5 V	GND	4.5 V			-	Q5			
			56	"							"				GND	4.3 V	4.5 V	GND	"	Q5 Q6			
	Icc	3005	57	5.5 V		5.5 V	5.5 V		5.5 V					5.5 V		5.5 V	5.5 V	GIND	-	V <sub>CC</sub>		26	
2		ests, termina			e as for sub			- ±125°€ :		te are om	itted	l		J.J V		J.J V	J.J V	l .	Į	V CC		20	
		ests, termina																					
7 <u>5</u> /, <u>6</u> /	Truth	3014	58	B B	3 a5 101 SUL	A A	A A	33 C an	A A	l I	GND	Α	1	Α	1	Α	Α		4.5 V	All		See <u>7</u> /	
Tc = 25°C	table	"	59	"	-	"	"	-	"	-	UIVD "	В	-	"	-	- "	"	-	T.5 V	outputs		"	
10 - 23 0	tests		60		-							A		"					-	"		-	
	10313		61	Α	"	"	"	"	"	"	"	A		"						"			
			62		"	"	"	"	"	"	"	В		"						"			
			63	"	Н	"	"	Н	"	Н	"	A	Н	"	Н			Н		"			
			64	"	"	В	В	"	В	"	"	A	- ;	В	- "	В	В			"			
			65		"	"	"	"	"	"	"	В		ı,		"	"			"			
			66	"	L	"	"	L	"	L	"	Ā	L	"	L	"	"	L	"	"			
			67	"	Ī	Α	Α	Ē	Α	L	"	В		Α	Ī	Α	Α	Ī	"	"			
			68	"	Н	"	"	Н	"	H	"	A	H	"	H	"		Н	"	"			
			69	"	Н	"	"	Н	"	Н	"	В	H	"	H	"		Н	"	"			
		"	70	В	L	"	"	L	"	L	"	В	L	"	L	"	"	L	"	"			
8	Repeat	subgroup 7	at T <sub>C</sub> = +125	5°C and T₀	c = -55°C.	•					•					•							
9	f <sub>MAX</sub>	Fig. 13	71	2.7 V	OUT	IN					GND	IN							5.0 V	Q1	25		MHz
Tc = 25°C		"	72	"			IN	OUT			"								"	Q2			
		"	73	"					IN	OUT	"								"	Q3			
		"	74	"							"		OUT	IN					"	Q4	"		
		"	75	"							"				OUT	IN			"	Q5			
		"	76	"							"						IN	OUT	"	Q6			
	t <sub>PHL1</sub>	3003	77	IN							"						2.7 V	OUT	"	CLR to Q6	5	42	ns
		Fig. 13	78								"				OUT	2.7 V			"	CLR to Q5	"	"	"
		"	79	"							"		OUT	2.7 V					"	CLR to Q4	"	"	"
	1	"	80	"					2.7 V	OUT	"								"	CLR to Q3	"	"	"
		"	81	"			2.7 V	OUT			"	"							"	CLR to Q2		"	
		"	82	"	OUT	2.7 V					"	"							"	CLR to Q1		"	"
	t <sub>PLH2</sub>	3003	83	2.7 V	OUT	IN						-							"	CLK to Q1		37	
		Fig. 14	84				IN	OUT											"	CLK to Q2		"	
			85						IN	OUT			OUT						- "	CLK to Q3			
	1		86		<u> </u>								OUT	IN	OUT				<u>"</u>	CLK to Q4			-
			87		ļ										OUT	IN	INI	OUT	L	CLK to Q5			-
	4	3003	88 89								- "	-					IN	OUT	-	CLK to Q6	-	- 40	
	t <sub>PHL2</sub>			-	-						-	-			OUT	INI	IN	001	- "	CLK to Q6		40	
		Fig. 15	90	"	<b> </b>							-	OUT	18.1	OUT	IN			-	CLK to Q5		-	
			91 92	"	-				INI	OUT	"		OUT	IN						CLK to Q4	-	-	-
				"	-		INI	OUT	IN	OUT	"									CLK to Q3	-		-
		,,	93 94	"	OUT	IN	IN	001			"									CLK to Q2 CLK to Q1	-		
	l	L	94	l	UUI	IIN					l	l				l		l	1	CLN IO QT			

See footnotes at end of device types 06.

Terminal conditions (p	ina nat daair	wastad may bal	1 ab > 2 0 V	\ \au < 0 7 \\ ar anan\
Terminal conditions to	ins noi desid	mareo may be i	110N / /.U V	. low < 0.7 v. or open.

		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
Subgroup	Symbol	883 method	Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Lim	its	Unit
			Test no.	CLR	Q1	D1	D2	Q2	D3	Q3	GND	CLK	Q4	D4	Q5	D5	D6	Q6	V <sub>cc</sub>		Min	Max	
10	f <sub>MAX</sub> <u>8</u> /	Fig. 13	95-100																		25		MHz
	t <sub>PHL1</sub>	3003 Fig. 13	101-106	Same tes	ts and ter	minal cond	litions as f	or subgrou	ıp 9, excei	ot T <sub>C</sub> . T <sub>C</sub> =	= +125°C									•	5	52	ns
	t <sub>PLH2</sub>	3003 Fig. 14	107-112					Ü												•	"	47	"
	t <sub>PHL2</sub>	3003 Fig. 15	113-118																		"	52	"

1/ Case X and 2 pins not referenced are NC. 2/ - - - 2.5 V minumum/5.5 V maximum

3/ I<sub>IL</sub> limits in mA are as follows:

56

			Mi	n/Max limits for	CKT		
$I_{\rm IL1}$	Α	В	С	D	Е	F	G
	085/270	100/340	075/250	075/250	120/360	160/400	075/250

			Mi	n/Max limits for	CKT		
$I_{IL2}$	Α	В	С	D	Ш	F	G
	115/350	150/420	125/275 for test 33 160/400 for test 34	120/360	120/360	150/380 for test 33 160/400 for test 34	075/250 for test 33 120/360 for test 34

2.5 V minumum/5.5 V maximum

- 5/ Input voltages shown are A = 2.0 volts minimum and B = 0.7 volts maximum.
- 6/ Tests shall be performed in sequence, attributes data only.
- $\overline{2}$ / Output voltages shall be H  $\geq$  1.5 V and L < 1.5 V.
- 8/ f<sub>MAX</sub> minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.

TABLE III. Group A inspection for device type 07. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	5	7	8	9	10	12	e nign ≥ 13	14	15	17	18	19	20				
Subgroup	Symbol		Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Lin	nits	Unit
		metriod	Test no.	CLR	Q1		D1	D2	Q2	Q2	GND	CLK	Q3	Q 3	D3	D4		Q4	V <sub>CC</sub>	terminar	Min	Max	
1	V <sub>OH</sub>	3006	1	0.7 V		4 mA					GND								4.5 V	_ Q1	2.5		V
Tc = 25°C		"	2	"					4 mA		"									_ Q2			"
		"	3	"							"			4 mA					"	Q3			"
		"	4	"							"						4 mA			- Q4			
			5	2.0 V							"	<u>2</u> /				2.0 V		4 mA		Q4 Q4			"
		"	6	"							"	-	4 mA		2.0 V	2.0 1		110 (		Q3			"
		"	7	"				2.0 V		4 mA	"	"							"	Q2	"		"
		"	8	"	4 mA		2.0 V				"									Q1			"
		"	9			4 mA	0.7 V				"	"								Q1			
		"	10	"				0.7 V	4 mA		"	"								_ Q2			"
		"	11	"							"	"		4 mA	0.7 V					_ Q 3			"
		"	12	"							"	"				0.7 V	4 mA		"	_ Q4	"		"
	V <sub>OL</sub>	3007	13	0.7 V	4 mA						"									Q1		0.4 V	"
	OL.	"	14	"						4 mA	"								"	Q2		"	"
		"	15	"							"		4 mA							Q3		"	"
			16	"							"	2/						4 mA		Q4			
		,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	17	2.0 V							"					2.0 V	4 mA			_ Q4			
		"	18	"							"	"		4 mA	2.0 V					Q 3		"	"
		"	19	"				2.0 V	4 mA		"	"								_ Q2		"	"
		"	20	"		4 mA	2.0 V				"	"							"	_ Q1		"	"
		"	21	"	4 mA		0.7 V				"	"							"	Q1		"	"
		"	22	"				0.7 V		4 mA	"	"							"	Q2		"	"
		" "	23	"							"	"	4 mA		0.7 V	0.71/			- "	Q3		"	- "
	V <sub>IC</sub>		24 25	-18 mA							"					0.7 V		4 mA	-	Q4 CLR		-1.5 V	-
	V IC		26	-101117			-18 mA				"									D1		-1.5 V	
			27					-18 mA			"									D2		"	"
			28								"	-18 mA								CLK		"	"
			29								- "				-18 mA					D3			
	<u> </u>	3009	30 31					<del>                                     </del>			"			<u> </u>		-18 mA 0.4 V			5.5 V	D4 D4	3/	3/	mA
	I <sub>IL1</sub>	3009	32								"				0.4 V	U.4 V			0.0 V	D3	<u>3/</u>	<u>3</u> /	IIIA "
		"	33					0.4 V			"				U. T V				"	D2		"	
	<u></u>	"	34				0.4 V				"								"	D1	"	"	
	I <sub>IL2</sub>	"	35 36	0.4 V				_			"	0.4 V						_	"	CLR CLK	-	"	-
	I <sub>IH1</sub>	3010	36	2.7 V							"	U.4 V		-		<del>                                     </del>				CLR	<del>                                     </del>	20	μА
		"	38				2.7 V				"								"	D1		"	μΛ
		"	39					2.7 V											"	D2		"	"
		"	40								"	2.7 V							"	CLK		"	"
			41								- "				2.7 V	0.71:			- "	D3		"	
	<u> </u>		42			L	L		L					L		2.7 V			"	D4			

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See footnotes at end of device type 07.

# TABLE III. Group A inspection for device type 07 - Continued. Terminal conditions (pins not designated may be high $\geq 2.0 \text{ V}$ , low $\leq 0.7 \text{ V}$ , or open).

Substitution   Subs							Te	erminal o	conditio	ns (pins	not des	signated	∣may b	e high ≥	2.0 V, k	$5w \le 0.7$	V, or op	en).						
Part   Part			MIL-STD-		2	3		5	7	8	9	10	12	13	14	15	17	18	19	20				
Te = 25°C	Subgroup	Symbol		Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Lim	its	Unit
Te = 25°C					CLR	Q1	Q1	D1	D2	Q2	Q2		CLK	Q3	Q 3	D3		_ Q4	Q4			Min		
1	1	I <sub>IH2</sub>	3010									GND					5.5 V			5.5 V			100	μΑ
March   Marc	$Tc = 25^{\circ}C$		"									"				5.5 V				"			"	
1			"									"	5.5 V							"			"	"
Second Color   Seco			"						5.5 V			"								"			"	
Log   3011   49   6ND			"					5.5 V				"								"			"	"
Second Control   Seco			"									"								"			"	"
Same tests, terminal conditions, and items as for subgroup 1, except 17 = -55°C and 18   1   1   1   1   1   1   1   1   1		Ios	3011		GND		GND					"								"		-15	-100	mA
Second Control   Seco			"		"					GND		"								"		"	"	"
Second Column			"		"							"			GND							"	"	"
Second Column			"		"							"						GND		"		"	"	"
Second Color   Seco			"		4.5 V							"	<u>4</u> /				4.5 V		GND	"		"	"	"
C			"		"							"	"	GND		4.5 V				"			"	"
To   Second Control			"		"				4.5 V		GND	"	"							"			"	"
Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = +1/25°C and V <sub>C</sub> tests are omitted.			"		"	GND							"							"			"	"
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $												"				5.5 V	5.5 V			"	$V_{CC}$		18	"
T S																								
To = 25°C   table   * 59	3		ests, termina								are omitt	ed.												
Tests   Fig. 13   Fig. 14   Fig. 15   Fig. 1	7 <u>5</u> /, <u>6</u> /		3014		В	L	Н	Α	Α	Н	L	GND		L	Н	Α	Α	Н	L	4.5 V			See <u>7</u> /	
	$T_C = 25^{\circ}C$							"	"	"		"		"	"		"	"		"	outputs		"	
		tests					-	"	"	"	"	"		"	"	"	"			"	"		"	
84/5   Repeat subgroup 7 at Tc = 125°C and Tc = 55°C.   9			"		Α		"	"	"	"	"	"		"	"	"	"			"	"		"	
Bd/S   Repeat subgroup 7 at Tc = +125°C and Tc = -55°C.   Fig. 13   Ti			"		"	Н	L	"	"	L		"		Н	L		"	L	Н	"	"		"	
8 4/. 5/   Repeat subgroup 7 at T <sub>C</sub> = +125°C and T <sub>C</sub> = -55°C.   8 4/. 5/   Repeat subgroup 7 at T <sub>C</sub> = +125°C and T <sub>C</sub> = -55°C.   9			"			"	"	"	"	"	"	"			"		"			"	"		"	
66					"		"	В		"		"		-		В	В			"	"			
B d/, 5/   Repeat subgroup 7 at T <sub>C</sub> = +125°C and T <sub>C</sub> = -55°C.   S d d d d d d d d d d d d d d d d d d					"	L	Н	"	"	Н	L	"		<u>L</u>	Н		"	Н	L	"				
1						"			. "	"	"	"			"					"				
B   B   C   Fig. 13   Fig. 14   Fig. 15   Fi					"			Α	A							Α	Α			- "				
Note   Note							L.	- "	- "	L.		- "			L		- "	<u>L</u>						
Repeat subgroup 7 at T <sub>c</sub> = +125°C and T <sub>c</sub> = -55°C.   Signature						L.			L.	H	<u> </u>			L.			L.	<u> </u>	<del>- "</del>					
9 T <sub>C</sub> = 25°C g/g/ Fig. 13	0.4/.5/		L				Н			Н	L		В	L	Н			Н	L		"			
Tc = 25°C 8/												OND								501/	0.1	0.5		
Total   Tota		T <sub>MAX</sub>	Fig. 13		2.7 V	001	OUT					GND "	IN "							5.0 V		25		MHZ "
T4	1 <sub>C</sub> = 25°C	<u>o</u> /					001	IIN	IN.	OUT														
1										001														
Total   Tota					"				IN		OUT		- "											
# 77 " " " " " " " " " " " " " " " " " "			"										- "	OUT	OUT.					- "				
Total   Tota			"		, ,										001	IN						"		"
tp://ii         3003         79         IN         """"""""""""""""""""""""""""""""""""			"		"							"	"					OUT				"		"
Fig. 13 80 " " " OUT 2.7 V " " CLR to Q2 " " " CLR to Q2 " " " " CLR to Q2 " " " " CLR to Q2 " " " " CLR to Q2 " " " " CLR to Q2 " " " " " CLR to Q2 " " " " " " CLR to Q2 " " " " " " " CLR to Q2 " " " " " " " " " CLR to Q2 " " " " " " " " " " " " " " " " " "			"		"							"	"						OUT	"		"		"
81		t <sub>PLH1</sub>			IN							"	"				2.7 V	OUT			CLR to Q4	5	32	ns
CLR to Q2			Fig. 13		"							"	"		OUT	2.7 V				"	CLR to Q 3	"	"	"
" 82 " OUT 2.7 V " " " CLR to Q1 " " "			"	81	"				2.7 V	OUT		"	"							"	CLR to Q2	"	"	"
			"	82	"		OUT	2.7 V				"	"							"	CLR to Q1	"	"	"

See footnotes at end of device type 07.

TABLE III. <u>Group A inspection for device type 07</u> - Continued.

Terminal conditions (pins not designated may be high > 2.0 V, low < 0.7 V, or open).

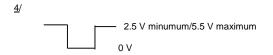
						Τe	erminal	conditio	ns (pins	not des	signated	l may b	e high ≥	2.0 V, k	$5.0 \ge wc$	V, or op	en).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
Subgroup	Symbol	883 method	Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Lim	nits	Unit
			Test no.	CLR	Q1	_ Q1	D1	D2	Q2	Q2	GND	CLK	Q3		D3	D4	_ Q4	Q4	V <sub>CC</sub>		Min	Max	Ì
9	t <sub>PHL1</sub>	3003	83	IN	OUT		2.7 V				GND	IN							5.0 V	CLR to Q1	5	45	ns
Tc = 25°C		Fig. 13	84	"				2.7 V		OUT	"	"							"	CLR to Q2	"	"	"
		"	85	"							"		OUT		2.7 V				"	CLR to Q3	"	"	"
		"	86	"							"					2.7 V		OUT		CLR to Q4	"	"	
	t <sub>PLH2</sub>	3003	87	2.7 V							"					IN		OUT	"	CLK to Q4	"	35	"
		Fig. 14	88	"							"	"	OUT		IN				"	CLK to Q3	"	"	
		"	89	"				IN		OUT		- "								CLK to Q2			<u> </u>
			90	"	OUT	OUT	IN				- :	-		ļ					- "	CLK to Q1			— <u>:</u>
		3003	91			OUT	IN													CLK to Q1			
		Fig. 15	92					IN	OUT			"							"	CLK to Q2		"	
		"	93	"							"	"		OUT	IN				"	CLK to Q 3	"	"	
		"	94	"							"					IN	OUT		"	CLK to Q4	"	"	"
	t <sub>PHL2</sub>	3003	95	"							"	"				IN	OUT		"	CLK to Q4	"	40	"
		Fig. 14	96								"	"		OUT	IN				"	CLK to Q 3		"	"
		"	97	"				IN	OUT		"								"	CLK to Q2	"	"	
		"	98	"		OUT	IN				"								"	CLK to Q1		"	
		3003	99		OUT		IN												"	CLK to Q1		"	
		Fig. 15	100					IN		OUT									"	CLK to Q2		"	"
		"	101	"							"		OUT		IN					CLK to Q3		"	"
		"	102	"							"	"				IN		OUT	"	CLK to Q4	"	"	"
10	f <sub>MAX</sub> 8/	Fig. 13	103-110																		25		ns
	t <sub>PLH1</sub>	3003	111-114																		5	51	"
	t <sub>PHL1</sub>	Fig. 13 3003	115-118	Same tes	sts and ter	minal cond	ditions as f	for subgro	up 9, exce <sub>l</sub>	ot T <sub>C</sub> = +1	25°C										"	55	"
	t <sub>PLH2</sub>	Fig. 13 3003	119-122					-												j		46	-
		Fig. 14																					<u> </u>
	t <sub>PLH2</sub>	3003 Fig. 15	123-126																		"	46	. "
	t <sub>PHL2</sub>	3003	127-130																		"	55	"
	t <sub>PHL2</sub>	Fig. 14 3003	131-134																			55	"
44	-	Fig.15		L																			
11	Same te	ests, termina	al conditions	, and limits	s as for su	ogroup 10,	except T <sub>0</sub>	<sub>c</sub> = -55°C.															

See footnotes at end of device type 07.

- 1/ Case X and 2 pins not referenced are NC. 2/ - - 2.5 V minumum/5.5 V maximum
- $\underline{3}/\ I_{\text{IL}}$  limits in mA are as follows:

			Mir	n/Max limits for 0	CKT		
I <sub>IL1</sub>	Α	В	С	D	E	F	G
	075/250	100/340	075/250	075/250	120/360	160/400	075/250

			Mi	n/Max limits for	CKT		
I <sub>IL2</sub>	Α	В	С	D	E	F	G
	085/270	150/420	125/275	120/400	120/400	105/380	075/250
	for test 35		for test 35	for test 35		for test 35	for test 35
	135/400		160/400	120/360		160/400	120/360
	for test 36		for test 36	for test 36		for test 36	for test 36



- 5/ Input voltages shown are A = 2.0 volts minimum and B = 0.7 volts maximum.
- 6/ Tests shall be performed in sequence, attributes data only.
- $\underline{7}/$  Output voltages shall be H  $\geq$  1.5 V and L < 1.5 V.
- g/ f<sub>MAX</sub> minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.

TABLE III. <u>Group A inspection for device type 09</u>. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

						16	illilliai (	Jonattio	na (hina	Hot des	signated	i illay b	e high ≥	2.0 V, IC	JW ≥ U.7	v, or op	en).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
Subgroup	Symbol	883 method	Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Lim	iits	Unit
			Test no.	CLR1	J1	_ K 1	CLK1	PR1	Q1	_ Q1	GND	_ Q 2	Q2	PR2	CLK2		J2	CLR2	V <sub>CC</sub>		Min	Max	
1	V <sub>OH</sub>	3006	1	0.7 V	0.7 V	0.7 V	GND	2.0 V		-4 mA	GND								4.5 V	_ Q1	2.5		V
Tc = 25°C		"	2	2.0 V	"	"	GND	0.7 V	4 mA		"								"	Q1	"		"
		"	3	"	"	"	<u>2</u> /	2.0 V		4 mA									"	_ Q1	"		
		"	4	"	2.0 V	2.0 V	2/	2.0 V	4 mA		"									Q1	"		
		"	5								"	4 mA		2.0 V	GND	0.7 V	0.7 V	0.7 V	"	Q 2	"		"
		"	6								"		4 mA	0.7 V	GND			2.0 V	"	Q2	"		"
		"	7								"	4 mA		2.0 V	<u>2</u> /	"			"	Q 2	"		"
		"	8								"		4 mA	"	2/	2.0 V	2.0 V			Q2			"
	V <sub>OL</sub>	3007	9								"		4 mA	"	GND	0.7 V	0.7 V	0.7 V	"	Q2		0.4	"
		"	10								"	4 mA		0.7 V	GND	"		2.0 V	"	Q 2		"	"
		"	11								"		4 mA	2.0 V	2/	"			"	Q2			"
		"	12								"	4 mA		2.0 V	<u>2</u> /	2.0 V	2.0 V			_ Q 2			"
		"	13	0.7 V	0.7 V	0.7 V	GND	2.0 V	4 mA										"	Q1		"	"
		"	14	2.0 V	"	"	GND	0.7 V		4 mA									"	Q1			"
		"	15	"	"	"	2/	2.0 V	4 mA		"									Q1		"	
		"	16	"	2.0 V	2.0 V	<u>2</u> /	2.0 V		4 mA	"									Q1		"	"
-	V <sub>IC</sub>		17	-18 mA							"									CLR1		-1.5	
	10		18		-18 mA						"								"	J1		"	"
			19			-18 mA																	
			20				-18 mA				"								"	CLK1			
			21					-18 mA			"								"	PR1			
			22								-			-18 mA					-	PR2		-	
			23												-18 mA	40. 4				CLK2		-	
			24													-18 mA				_ K 2		-	
			25								"						-18 mA			J2		-	
l -		0000	26	0/	0.41/	451/	OND	451/			- :							-18 mA	5.5.7	CLR2	4/	4/	
	I <sub>IL2</sub>	3009	27 28	<u>3</u> / 4.5 V	0.4 V 4.5 V	4.5 V 0.4 V	GND GND	4.5 V 3/			"								5.5 V	J1 - K 1	<u>4/</u>	<u>4/</u>	mA "
		"	29											3/	GND	0.4 V	4.5 V	4.5 V		K 1			
		"	30											4.5 V	GND	4.5 V	0.4 V	3/		J2			
-	I <sub>IL4</sub>	"	31								"			4.5 V	0.4 V	4.5 V	4.5 V	3/		CLK2	"		
	-1124	"	32								"			3/	0.4 V	"	"	4.5 V	"	CLK2	"		
		"	33								"			0.4 V	4.5 V	"	"	GND	"	PR2	"	"	"
		"	34	GND	4.5 V	4.5 V	4.5 V	0.4 V											"	PR1	"	"	"
			35	4.5 V	"		0.4 V	<u>3</u> /			- "								- "	CLK1	- "		- "
1 -	I <sub>IL7</sub>	"	36 37	<u>3</u> / 0.4 V	"		0.4 V 4.5 V	4.5 V GND												CLK1 CLR1		-	
			31	U.4 V			4.5 V	GIVD						GND		4.5 V				CLR1			1

See footnotes at end of type 09.

TABLE III. <u>Group A inspection for device type 09</u>. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

						16	erminai d	conaitio	ns (pins	not des	signated	ı may b	e high ≥	2.0 V, K	0.7	v, or op	en).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
Subgroup	Symbol	883 method	Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Lim	iits	Unit
			Test no.	CLR1	J1	<del>-</del> K 1	CLK1	PR1	Q1	Q1	GND	Q 2	Q2	PR2	CLK2	<del>-</del> K 2	J2	CLR2	V <sub>CC</sub>		Min	Max	
1	I <sub>IH1</sub>	3010	39	GND	2.7 V	GND	4.5 V	4.5 V			GND								5.5 V	J1		20	μΑ
Tc = 25°C		"	40	GND	GND	2.7 V	4.5 V	GND			"								"	_ K 1			"
		"	41								"			GND	4.5 V	2.7 V	GND	GND					
															4.0 1			OND		_ K 2			
		"	42								- "			4.5 V		GND	2.7 V			J2			
	I <sub>IH2</sub>	"	43								<u> </u>			4.5 V		GND	5.5 V	-:-		J2		100	
			44											GND		5.5 V	GND		-	_ K 2		-	
		"	45	GND	GND	5.5 V	4.5 V	GND			"								"				"
		,,	46	GND	5.5 V	GND	4.5 V	4.5 V												J1			
	I <sub>IH3</sub>	ıı ı	47	GND	4.5 V	4.5 V	2.7 V	GND											"	CLK1		40	"
	'IH3		48	4.5 V	4.5 V	4.5 V	GND	2.7 V											"	PR1		"	"
		"	49				0.15				"			2.7 V	GND	4.5 V	4.5 V	4.5 V	"	PR2		"	"
		"	50								"			GND	2.7 V	"	"	GND	"	CLK2		"	"
	I <sub>IH4</sub>	"	51								"			GND	5.5 V			GND	"	CLK2		200	"
		"	52								"			5.5 V	GND	"	"	4.5 V	"	PR2		"	"
		"	53	4.5 V	4.5 V	4.5 V	GND	5.5 V			"								"	PR1		"	"
		"	54	GND	4.5 V	4.5 V	5.5 V	GND			"								"	CLK1		"	"
	I <sub>IH7</sub>	"	55	2.7 V	4.5 V	4.5 V	GND	4.5 V			-:-				0115					CLR1		80	
		- "	56								- :			4.5 V	GND	4.5 V	4.5 V	2.7 V	- "-	CLR2		80	
	I <sub>IH8</sub>	,,	57 58	5.5 V	4.5 V	4.5 V	GND	4.5 V			-			4.5 V	GND	4.5 V	4.5 V	5.5 V	- "	CLR2 CLR1		400 400	
	Ios	3011	59	GND	4.5 V	4.5 V	GIND	4.5 V		GND											-15	-100	mA
	ios	3011	33	CIVE				7.5 V		GIVE										Q1	-13	-100	IIIA
		"	60	4.5 V				GND	GND		-								"	Q1	-	"	"
		"	61								"		GND	GND				4.5 V	"	Q2		"	"
		"	62								"	GND		4.5 V				GND	"	_ Q 2			"
	Icc	3005	63	GND			GND	5.5 V			"			5.5 V	GND			GND		V <sub>CC</sub>		8.0	
	ICC	3005	64	5.5 V			GND	GND			"			GND	GND			5.5 V	"	V <sub>CC</sub>		8.0	
2	Same te		al conditions		s as for sub	naroun 1			and V <sub>io</sub> tes	sts are om	itted	1		OND	OND	1		0.0 1	1	¥ CC	1	0.0	
3			al conditions																				
7 <u>5</u> /, <u>6</u> /	Truth	3014	65	A	A	Α Α	В	В	H	L	GND	L	Н	В	В	Α	Α	Α	4.5 V	All		See 7/	
Tc = 25°C	table	"	66	"		"	В	A	"	"	"			A	В	"			"	outputs		"	
	tests	"	67			"	Α	"	"	"				"	Α					,			
		"	68	"	"	В	Α				"	"		"	Α	В	"		"	"			
		"	69	"	"	"	В	"	"	"	"	"	"	"	В	"	"	"	"	"			
		"	70	"	"	"	Α	"	L	Н	"	Н	L	"	Α	"		"	"	"			
		"	71	- "	- "	- "	В	- "		- "	- "			- "	В	- "		-	- "-	"		-:-	
		"	72	В														В	<del></del>	- "			
		,,	73 74	A	- "	- "		- "		<del>                                     </del>	- "		H	- "			-	Α "	<del>-</del> -				
		,,	75	"	"	"	A B	"	H	L	"	L	H	"	A B				-	"			
		"	76	"	"	"	A	"	L	H	"	H	I I	"	A					"		-	
		"	77	"	"	"	В	"	Ĺ	H	"	H	Ĺ	"	В	"				"			
		"	78	"	"	"	В	В	H	Ĺ	"	L	H	В	В	"			"	"			
		"	79	"	"	"	A	В	"	"	"		"	В	A	"		"	"	"			
		"	80	"	"		Α	Α	"		"	"		Α	Α		"	"		"			
		"	81	"	"	"	В	"	"	"	"	"	"	"	В	"		"	"	"			
		"	82	"	"	"	Α	"	L	Н	"	Н	L	"	Α	-	-	"	"	"		"	
		"	83	"	"	"	В	"	"	"	"	"		"	В		-	"		"			
			84	В	В		"				- "	- "				- "	В	В				-	
			85	Α "	- "	- "		- "		- "		-					-	A				-	
	i		86	1 **	1 "		Α			**	1 **				Α				1 "		1	-	

See footnotes at end of device type 09.

TABLE III. <u>Group A inspection for device type 09</u>. Terminal conditions (pins not designated may be high  $\geq$  2.0 V, low  $\leq$  0.7 V, or open).

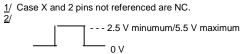
						16	erminai d	conaitio	ns (pins	not aes	signated	i may b	e nign ≥	2.0 V, K	$5 \text{ ow} \leq 0.7$	v, or op	en).						
		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
Subgroup	Symbol	883 method	Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Lim	nits	Unit
			Test no.	CLR1	J1	<del>-</del> K 1	CLK1	PR1	Q1	_ Q1	GND	_ Q 2	Q2	PR2	CLK2		J2	CLR2	V <sub>CC</sub>		Min	Max	
7 <u>5</u> /, <u>6</u> /	Truth	3014	87	Α	Α	В	Α	Α	L	Н	GND	Н	L	Α	Α	В	Α	Α	4.5 V	All		See 7/	
Tc = 25°C	table	"	88	"		"	В	"	"	"	"	"		"	В	"	"		"	outputs		"	
	tests	"	89	"	"		"	В	Η	L	"	L	Η	В		-	-			"			
		"	90	"	"	"	"	Α	Н	L	"	L	Η	Α	"					"		"	
			91	"	- "	"	A		L L	Н	"	H	L .	- "	Α	- "	-:-			- "			
			92		-:-	- "	B B	- :	- "	- :	- :	-:-		-:-	B B	<u> </u>	<u> </u>	В		- :		_;_	
			93 94	B B			A							"	A			В				-	
			95	A	"	"	A	"	"	"	"			"	A			A		"			
		"	96	"	"	"	В	"	"	"	"			"	В			-		"			
			97	"	В	Α	В	"	"	"	"			"	В	Α	В		"	"		"	
			98	"	В	"	Α	"	"	"	"	"		"	Α		В		"	"			
		"	99	"	Α	"	"	В	Н	L	"	L	Η	В	"		Α		"	"		"	
		"	100	"	"	"	"	Α	Н	L	"	L	Н	Α						"			
		"	101	В	"	"	"	Α	L	Н	"	Н	L	Α	"		"	В	"	"			
			102	A	В	В	В	В	H	L	"	L	H	В	В	В	В	A		"			
			103 104	A B	- "		- "	A	H L	H	- "	H	H	A A				A B					
8	Donoot (	subgroup 7			_ EE°C			А	L	п	l .	П	L	А				ь					
9	f <sub>MAX</sub>	Fig. 16	105	2.7 V	2.7 V	GND	IN	2.7 V	OUT		GND	1							5.0 V	Q1	20		MHz
Tc = 25°C	<u>8</u> /	"	106	2.7 V	2.7 V	GND	IN	2.7 V		OUT	"								"	Q1	"		"
		"	107								"	OUT		2.7 V	IN	GND	2.7 V	2.7 V	"	_ Q 2	"		"
		=	108								"		OUT	2.7 V	IN	GND	2.7 V	2.7 V	"	Q2	-		=
	t <sub>PLH1</sub>	3003	109	IN	2.7 V	2.7 V	IN	2.7 V		OUT	"								"	CLR1 to Q1	5	20	ns
		Fig. 17	110	2.7 V	GND	GND	IN	IN	OUT										"	PR1 to Q1		"	
			111										OUT	IN	IN	GND	GND	2.7 V	"	PR2 to Q2			
		"	112								"	OUT		2.7 V	IN	2.7 V	2.7 V	IN	. "	CLR2 to Q 2			
	t <sub>PHL1</sub>	"	113								"		OUT	2.7 V	IN	2.7 V	2.7 V	IN		CLR2 to Q2		32	"
		"	114								"	OUT		IN	IN	GND	GND	2.7 V	"	PR2 to Q 2		"	
		"	115	2.7 V	GND	GND	IN	IN		OUT									"	PR1 to Q1	"	"	
		"	116	IN	2.7 V	2.7 V	IN	2.7 V	OUT	1		-		1		1	1		"	CLR1 to Q1		"	"
	t <sub>PLH2</sub>	3003	117	2.7 V	2.7 V	GND	IN	2.7 V	OUT										"	CLK1 to Q1		24	"
	1 112	Fig. 16	118	2.7 V	2.7 V	GND	IN	2.7 V		OUT	"								"	CLK1 to Q1	"	"	"
		"	119								"	OUT		2.7 V	IN	GND	2.7 V	2.7 V	"	CLK2 to Q 2		"	"
		"	120								"		OUT	2.7 V	IN	GND	2.7 V	2.7 V	"	CLK2 to Q2		"	"
	t <sub>PHL2</sub>	"	121								"		OUT	2.7 V	IN	GND	2.7 V	2.7 V	"	CLK2 to Q2	"	35	"
		"	122								"	OUT		2.7 V	IN	GND	2.7 V	2.7 V	"	CLK2 to Q 2	"	"	
		"	123	2.7 V	2.7 V	GND	IN	2.7 V		OUT	"								"	CLK1 to Q1	"	"	"
		"	124	2.7 V	2.7 V	GND	IN	2.7 V	OUT		"								"	CLK1 to Q1	"	"	"

See footnotes at end of device type 09.

## TABLE III. Group A inspection for device type 09.

Terminal conditions (pins not designated may be high > 2.0 V. low < 0.7 V. or open).

		MIL-STD-	Cases <u>1</u> / 2, X	2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20				
Subgroup	Symbol	883 method	Cases E, F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	Measured terminal	Lim	nits	Unit
			Test no.	CLR1	J1	<del>-</del> 1	CLK1	PR1	Q1	Q1	GND	Q 2	Q2	PR2	CLK2	_ K 2	J2	CLR2	V <sub>CC</sub>		Min	Max	
10	f <sub>MAX</sub> 8/	Fig. 16	125-128			•								'							20		MHz
	t <sub>PLH1</sub>	3003 Fig. 17	129-132		ts and tern	minal cond	itions as fo	or subgroup	p 9, excep	t T <sub>C</sub> = +12	5°C.									•	5	39	ns
	t <sub>PHL1</sub>	3003 Fig. 17	133-136						•	-										•		59	
	t <sub>PLH2</sub>	3003 Fig. 16	137-140																			39	-
	t <sub>PHL2</sub>	3003 Fig. 16	141-144																			59	-
11	Same te	sts, termina	l conditions	, and limits	as for sub	bgroup 1, e	except T <sub>C</sub> =	= -55°C an	d V <sub>IC</sub> tests	are omitte	ed.												



3/ I<sub>IL</sub> limits in mA are as follows:

			Min/Max li	mits for CKT		
I <sub>IL2</sub>	Α	В	С	D	E	F
	075/250	030/300	095/210	160/400	135/370	160/400

	Min/Max limits for CKT					
I <sub>IL4</sub>	Α	В	С	D	Е	F
	150/500 for tests 31, 32, 35, 36 200/800 for tests 33,	060/700	160/400 for tests 31, 32, 35, 36 350/760 for tests 33,	320/800	120/360 for tests 31, 32, 35, 36 350/760 for tests 33,	320/800
	34		34		34	

	Min/Max limits for CKT						
I <sub>IL7</sub>	Α	В	С	D	Е	F	
	200/800	060/700	350/760	560/-1.600	280/760	560/-1.600	

<u>4</u>/ 2.5 V minumum/5.5 V maximum 0 V

- 5/ Input voltages shown are A = 2.0 volts minimum and B = 0.7 volts maximum.
- 6/ Tests shall be performed in sequence, attributes data only.
- $\overline{Z}/$  Output voltages shall be H  $\geq$  1.5 V and L < 1.5 V.
- g/ f<sub>MAX</sub> minimum limit specified is the frequency of the input pulse. The output frequency shall be one-half of the input frequency.

### 6. NOTES

- 6.1 <u>Intended use.</u> Microcircuits conforming to this specification are intended for original equipment design applications and logistic support of existing equipment.
  - 6.2 <u>Acquisition requirements.</u> Acquisition documents should specify the following:
    - a. Title, number, and date of the specification.
    - b. PIN and compliance identifier, if applicable (see 1.2).
    - c. Requirements for delivery of one copy of the conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.
    - d. Requirements for certificate of compliance, if applicable.
    - e. Requirements for notification of change of product or process to contracting activity in addition to notification to the qualifying activity, if applicable.
    - f. Requirements for failure analysis (including required test condition of method 5003 of MIL-STD-883), corrective action, and reporting of results, if applicable.
    - g. Requirements for product assurance options.
    - h. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements should not affect the part number. Unless otherwise specified, these requirements will not apply to direct purchase by or direct shipment to the Government.
    - i. Requirements for "JAN" marking.
    - Packaging requirements (see 5.1).
- 6.3 <u>Superseding information.</u> The requirements of MIL-M-38510 have been superseded to take advantage of the available Qualified Manufacturer Listing (QML) system provided by MIL-PRF-38535. Previous references to MIL-M-38510 in this document have been replaced by appropriate references to MIL-PRF-38535. All technical requirements now consist of this specification and MIL-PRF-38535. The MIL-M-38510 specification sheet number and PIN have been retained to avoid adversely impacting existing government logistics systems and contractor's parts lists.
- 6.4 <u>Qualification</u>. With respect to products requiring qualification, awards will be made only for products which are, at the time of award of contract, qualified for inclusion in Qualified Manufacturers List QML-38535 whether or not such products have actually been so listed by that date. The attention of the contractors is called to these requirements, and manufacturers are urged to arrange to have the products that they propose to offer to the Federal Government tested for qualification in order that they may be eligible to be awarded contracts or purchase orders for the products covered by this specification. Information pertaining to qualification of products may be obtained from DSCC-VQ, 3990 E. Broad Street, Columbus, Ohio 43123-1199.
- 6.5 <u>Abbreviations, symbols, and definitions.</u> The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535, MIL-HDBK-1331, and as follows:

GND	Ground zero voltage potential
l <sub>IN</sub>	Current flowing into an input terminal
V <sub>IC</sub>	Input clamp voltage
V <sub>IN</sub>	Voltage level at an input terminal

- 6.6 <u>Logistic support.</u> Lead materials and finishes (see 3.4) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class B (see 1.2.2), lead material and finish A (see 3.4). Longer length leads and lead forming shall not affect the part number.
- 6.7 <u>Substitutability.</u> The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-38510 device types and may have slight physical variations in relation to case size. The presence of this information shall not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-PRF-38535.

Military device type	Generic-industry type
01	54LS73
02	54LS74A
03	54LS112
04	54LS113
05	54LS114
06	54LS174
07	54LS175
08	54LS107
09	54LS109
10	54LS76A

6.8 <u>Manufacturers' designation.</u> Manufacturers' circuits, which form a part of this specification, are designated as shown in table IV herein.

TABLE IV. Manufacturers' designation.

	Manufacturers								
Device type	Texas Instru- ments Inc.	Signetics Corporation	National Semiconductor Corp	Raytheon Company	Motorola Inc	Fairchild Semiconductor	Advanced Micro Devices		
01	Α	В	С	D	Е				
02	Α	В	С	D	Е	F			
03	Α	В	С	С	D	Е			
04	Α	В	С	С	F	Е	D		
05	Α		С	С	D	Е			
06	Α	В	С	Е	F	G	D		
07	Α	В	С	Е	F	G	D		
08	Α	В	С	D	Е				
09	Α	В	С		Е	F			
10	Α	В	С	С	D	Е			

6.9 <u>Changes from previous issue.</u> The margins of this specification are marked with vertical lines to indicate where changes from the previous issue were made. This was done as a convenience only and the Government assumes no libility whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the marginal notations and relationship to the last previous issue.

Custodians:

Army - CR Navy - EC

Air Force - 11

DLA - CC

Preparing activity: DLA - CC

(Project 5962-2038)

Review activities:

Army - MI, SM Navy - AS, CG, MC, SH, TD Air Force - 03, 19, 99

NOTE: The activities listed above were interested in this document as of the date of this document. Since organizations and responsibilities can change, you should verify the currency of the information above using the ASSIST Online database at www.dodssp.daps.mil.